

ROC ASICs for timing

RD51 workshop 15 jun 2021

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- Jitter due to electronics noise:

$$\sigma_t^J = \frac{N}{\frac{dV}{dt}}$$

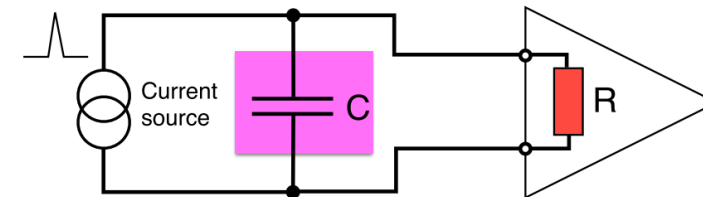
- also presented as $j = tr / (S/N)$
- dV/dt prop to BW, N prop to \sqrt{BW} \Rightarrow jitter prop to $1/\sqrt{BW}$

\Rightarrow « the faster the amplifier, the better the jitter ? »

\Rightarrow « High speed preamps need to be low impedance (50 Ω or less) ? »

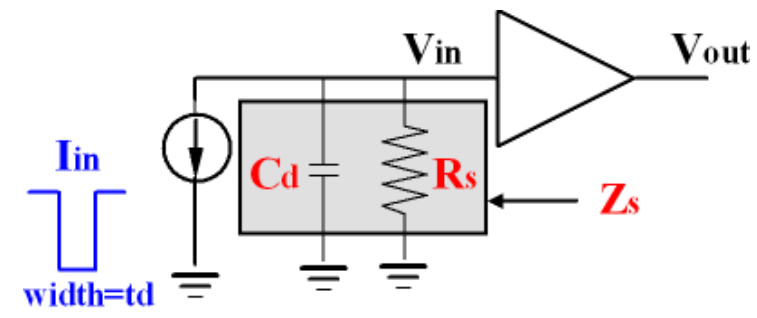
- minimize R_{PA} : small time constant $R_{PA} \cdot Cd$ « Minimize « charge time transfer »

NB : $tr = t_{10-90\%} = 2.2 \tau$.
 $f_{-3dB} = 1/2\pi\tau = 0.35 / t_{10-90}$
 $f_{-3dB} = 1 \text{ GHz} \leftrightarrow t_{10-90\%} = 300 \text{ ps}$
 $1 \text{ ps} = 300 \mu\text{m in vacuum}$

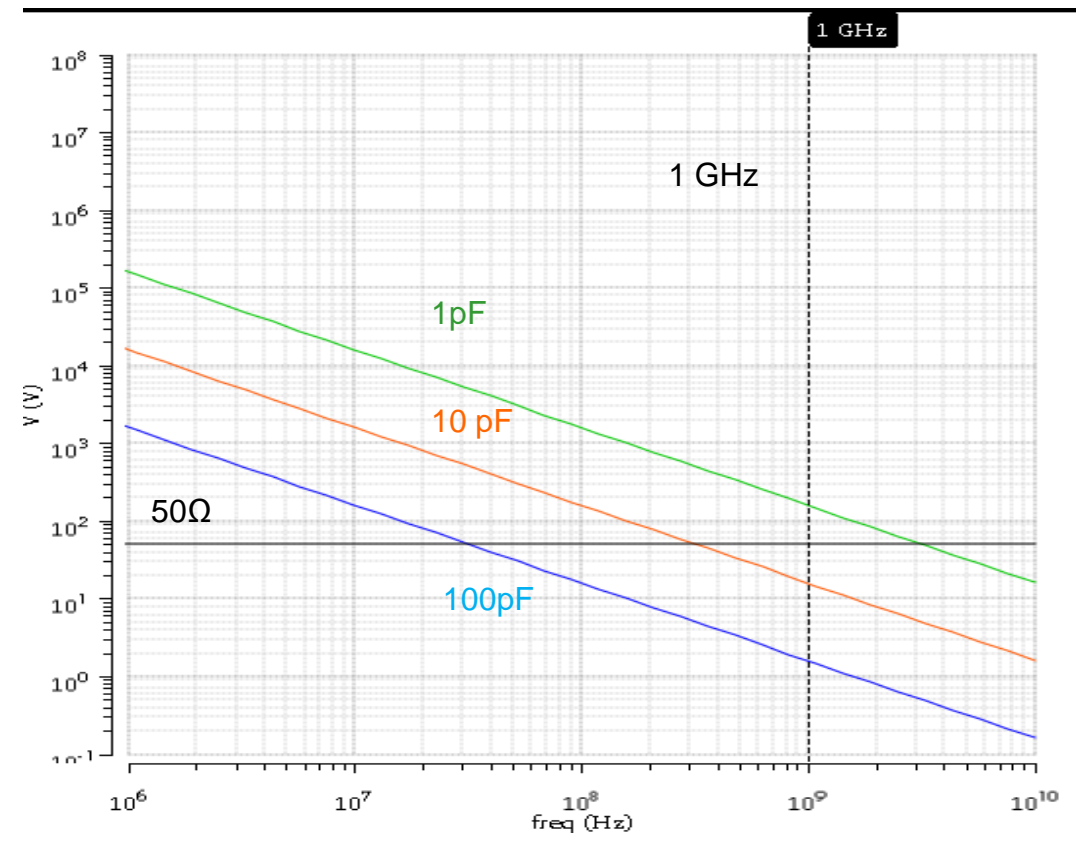
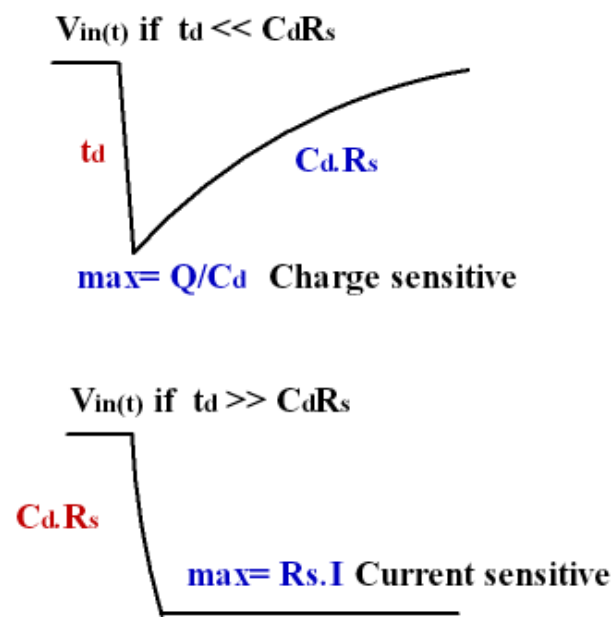


Detector impedance and input voltage

- 1 GHz, C_d =few tens of pF, input signal width <1ns
- $C_d > 1$ pF, Z_s @1GHz dominated by C_d
- Rise time: $t_r = t_d$ when $t_d \ll R_S C_d$ and $t_r = R_S C_d$ when $t_d \gg R_S C_d$

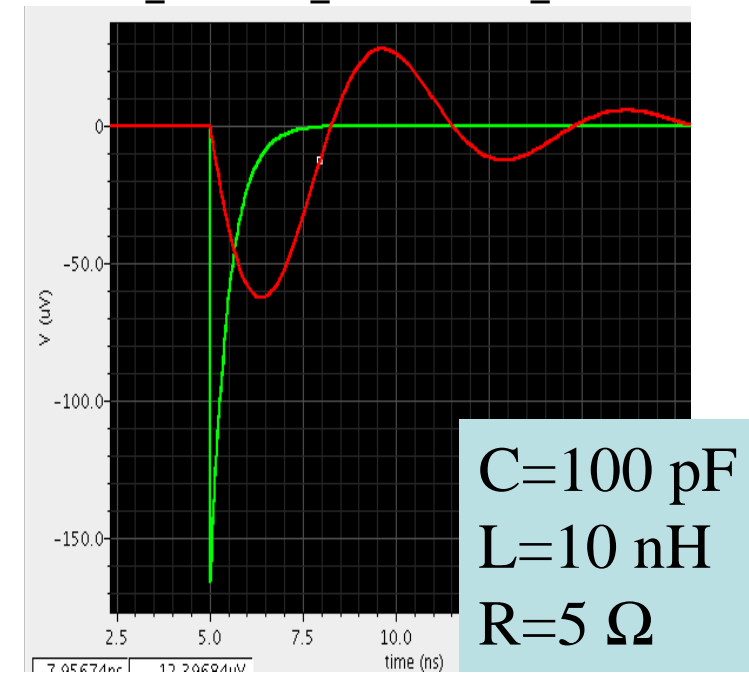
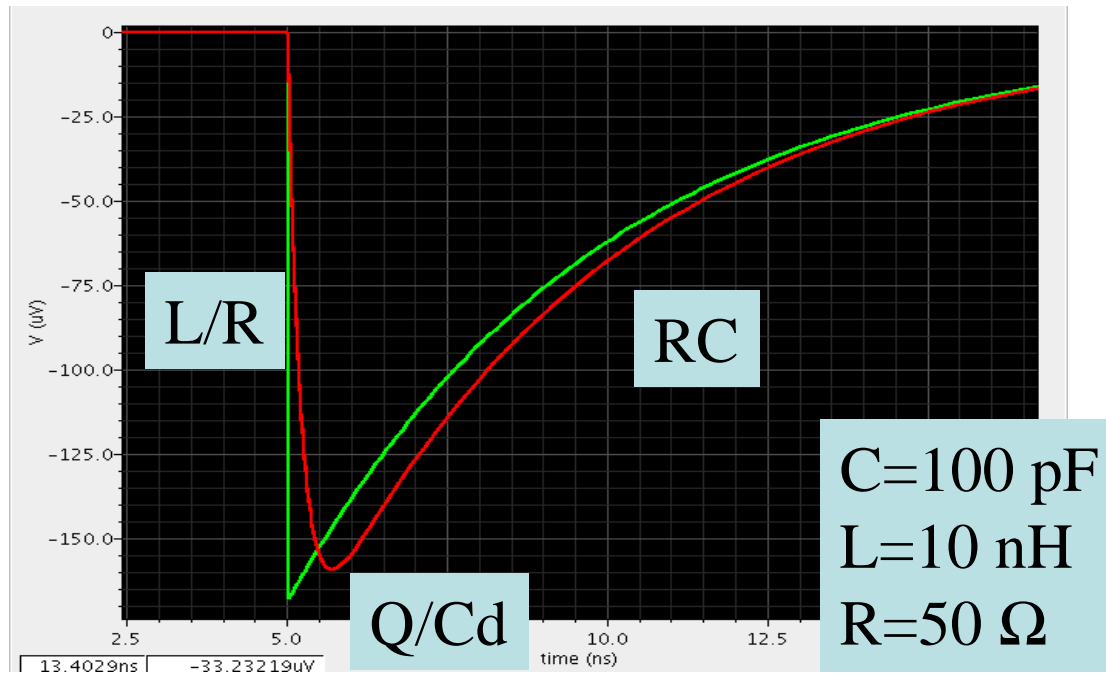
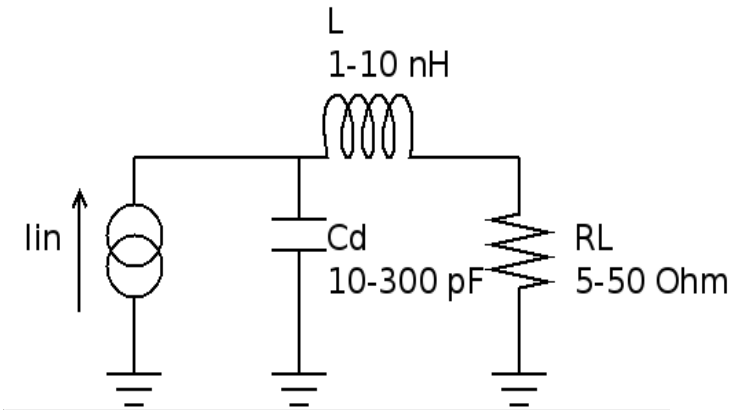


At HF : difficult to beat the capacitance => signal integrated on C_d



Examples of pulse shapes

- SiPM pulse : $Q=160$ fC, $C_d=100$ pF, $L=0-10$ nH, $R_{PA}=5-50$ Ω
- Sensitivity to parasitic inductance
- Choice of R_{PA} : decay time, stability
- Small R_{PA} not necessarily the fastest
- Convolve with current shape... (here delta)



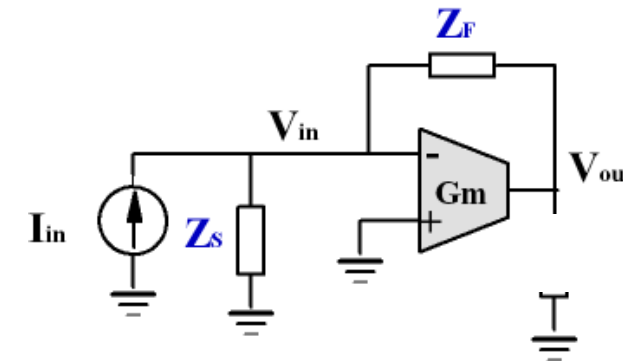
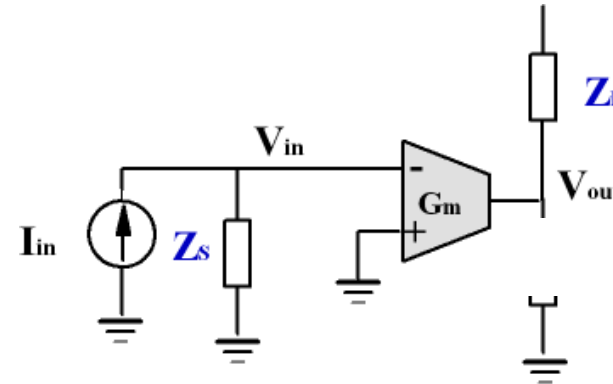
- Response to very short pulse
- Broadband : voltage sensitive
 - $Z_{in}=R_s$ (50 Ohm)
 - $V_{in} = Q/C_{in}$

$$- V_{OUT} = -G_m R_F \frac{Q_{IN}}{C_d}$$

- Transimpedance
 - $Z_{in} \sim Z_f/G \sim 1/g_m$

$$- V_{OUT} = \frac{\frac{1}{G_m} - R_F}{1 + j\omega \frac{C_d}{G_m}} I_{IN} \approx -G_m R_F \frac{Q_{IN}}{C_d}$$

- Same response at High Frequency
- For highest speed : go to broadband. Faster, less stability issues



Signal and noise in Broadband amplifiers

- Jitter is given by :

$$\sigma_t^J = \frac{N}{dV/dt} = \frac{e_n}{\sqrt{2t_{10-90_PA}}} \frac{C_d \sqrt{t_{10-90_PA}^2 + t_d^2}}{Q_{in}} = \frac{e_n C_d}{Q_{in}} \sqrt{\frac{t_{10-90_PA}^2 + t_d^2}{2t_{10-90_PA}}}$$

- Optimum value: $t_{10-90_PA} = t_d$ (current duration)

Dominated by sensor
Electronics only gives e_n

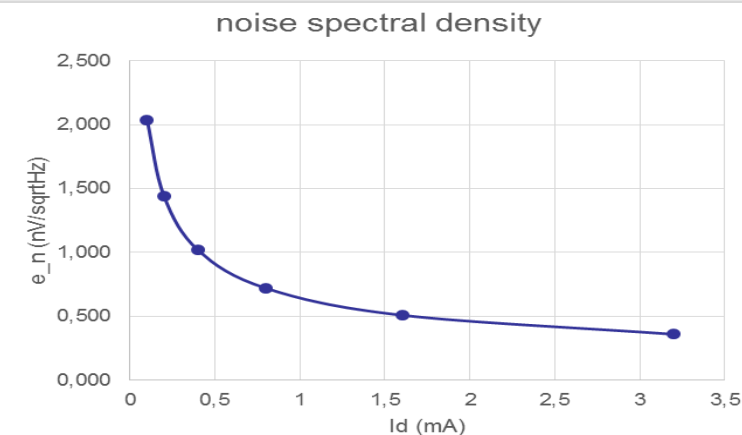
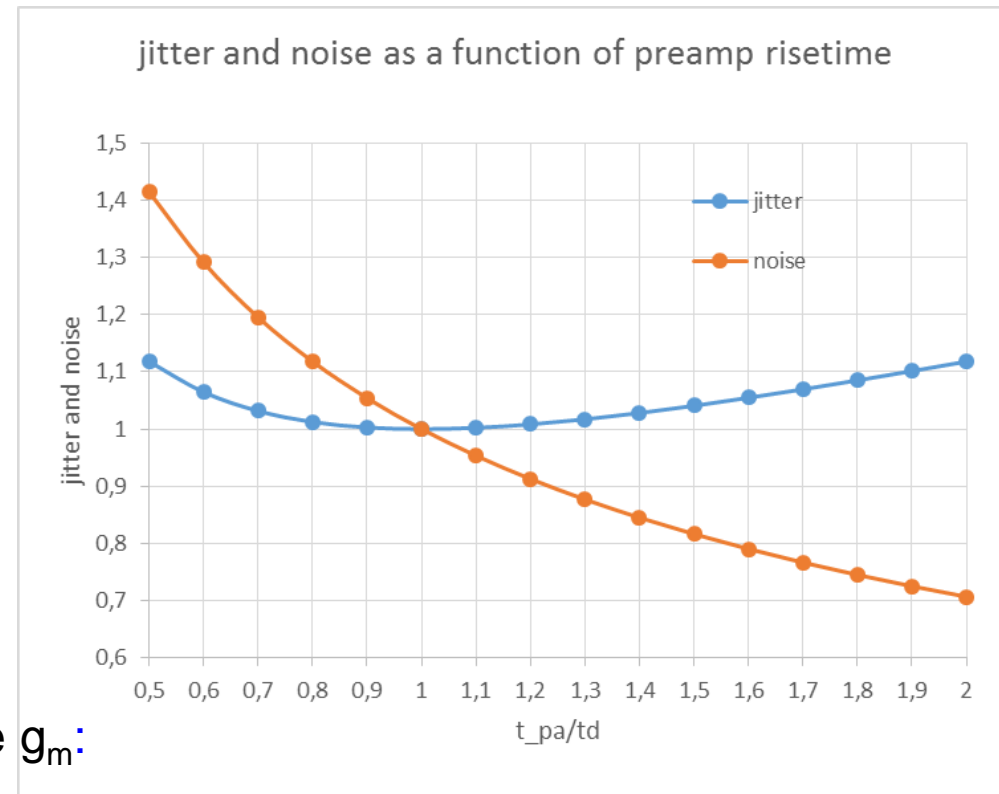
$$\sigma_t^J = \frac{e_n C_d}{Q_{in}} \sqrt{t_d}$$

C_d : detector capacitance
 t_{10-90_PA} : rise time of the PA
 t_d : detector current **duration**
 e_n : preamp noise density

- Gives **ps/fC** as scales with $1/Q_{in}$: « factor of merit »
- Electronics noise e_n given by the input transistor transconductance g_m :

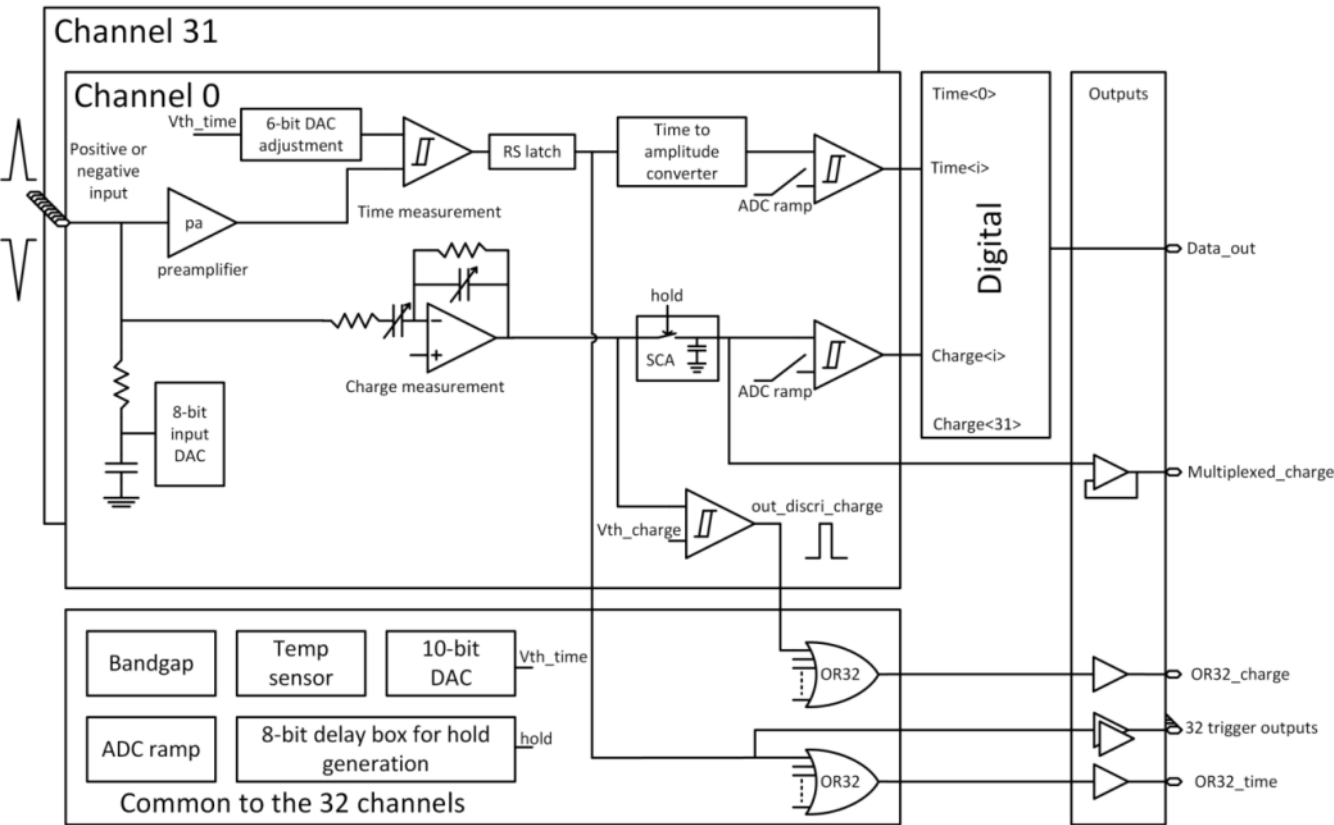
$$e_n = \sqrt{\frac{2kT}{g_m}} \approx \frac{2kT}{\sqrt{qI_D}}$$

- Jitter optimum is rather shallow with preamp risetime
- But noise and minimum threshold goes up quickly with speed (as sqrt)

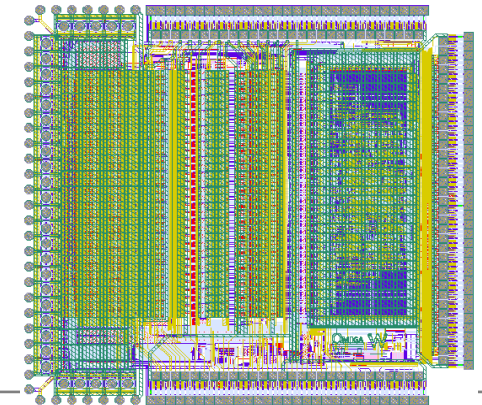


- See also presentation by Stéphane Callier on Thursday (Hardroc et al.)

		sensor	polarity	BW	Zin	Cd	TDC	dyn range	FOM	min thresh	"@Cd="
PETIROC	VPA	SiPM/RPC	both	900 MHz	200	10-100 pF	25 ps			1 mV	
LIROC	VPA	SiPM/RPC	both	300 MHz	1k	10-100 pF	no	10fC-100 pC	2 ns/Q (fC)	40 fC	
ALTIROC	VPA/TZ	LGAD	neg	300-800 MHz	2k/200	1-10 pF	20 ps	0.1-50 fC	100 ps/Q(fC)	2 fC	5 pF
HGCROC	TZ	Si	neg	100 MHz	40	10-100 pF	25 ps	0.1 fC-10 pC	2 ns/Q (fC)	20 fC	50 pF
H2GCROC	CC	SiPM	pos	80 MHz	25	100p-1nF	25 ps	10 fC-200 pC			



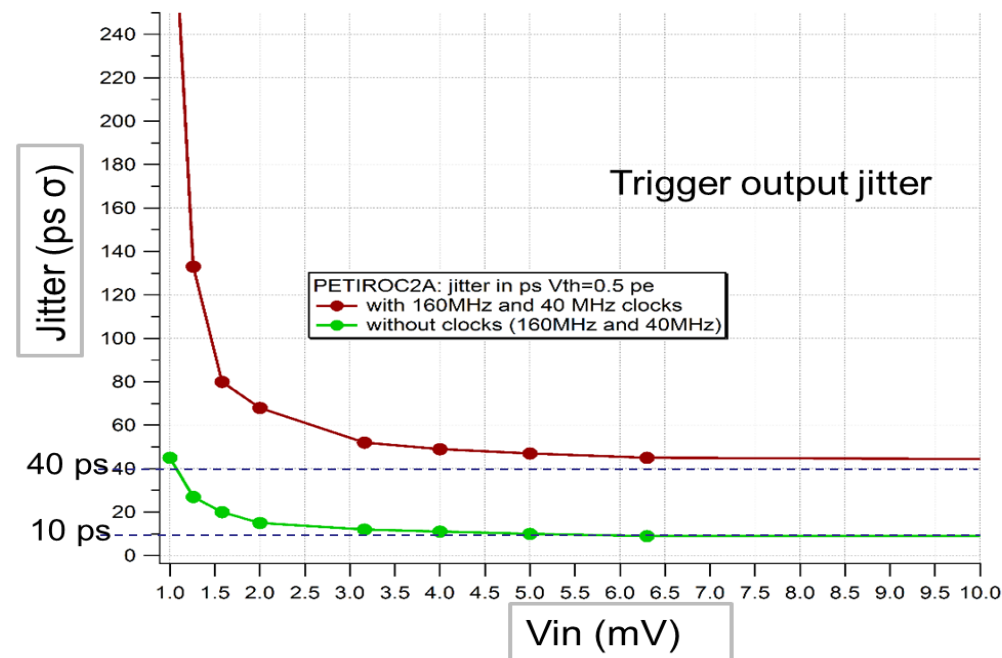
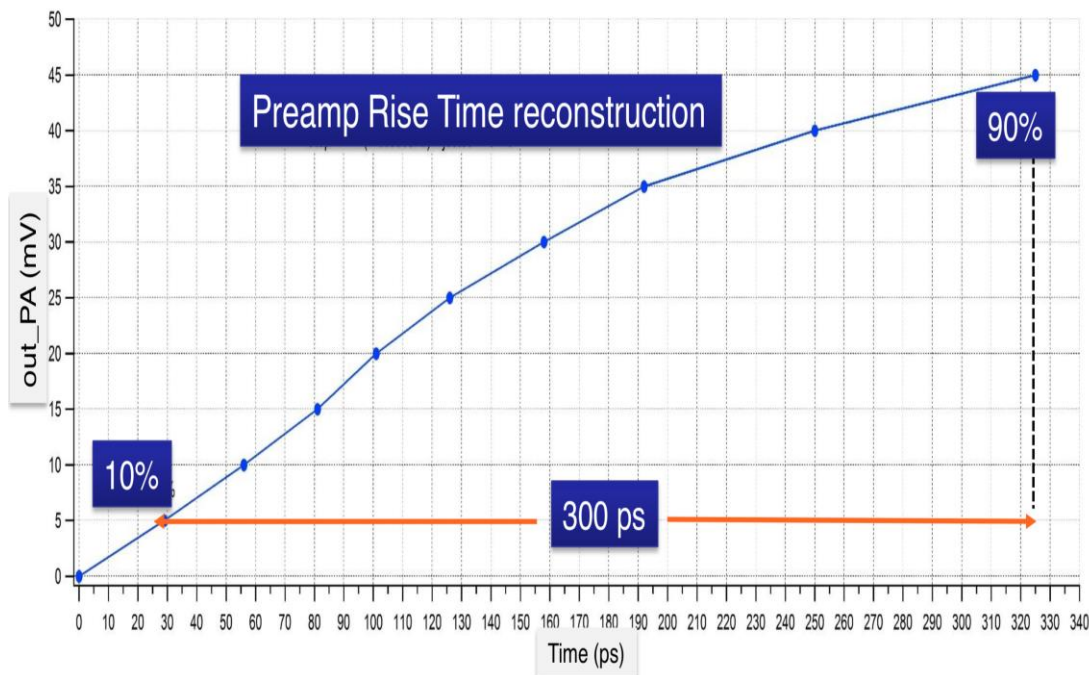
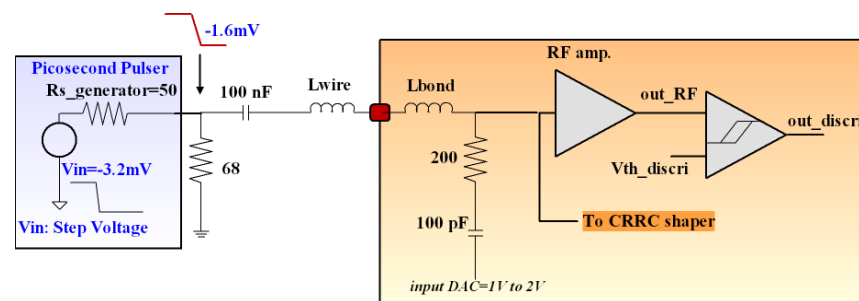
SiPM read-out for time-of-flight PET
SiGe 350 nm



Detector Read-Out	SiPM, SiPM array
Number of Channels	32
Signal Polarity	Positive or Negative
Sensitivity	Trigger on first photo-electron
Timing Resolution	~ 35 ps FWHM in analogue mode (2pe injected) - ~ 100 ps FWHM with internal
Dynamic Range	3000 photo-electrons (10^6 SiPM gain), Integral Non Linearity: 1% up to 2500 ph-e
Packaging & Dimension	TQFP160 – TFBGA353

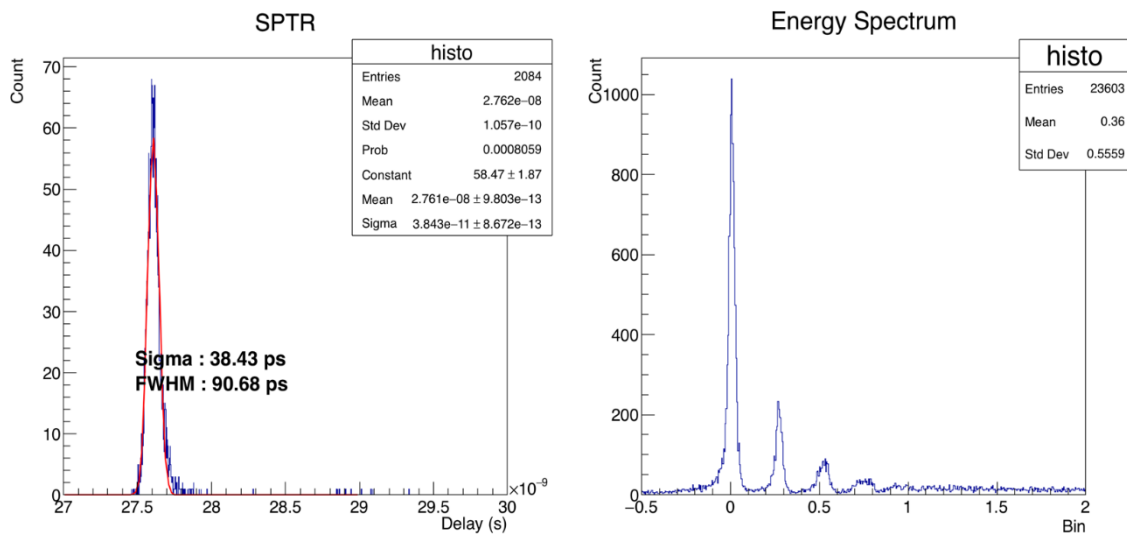
Petiroc2A bandwidth measurement

- Preamp + discriminator bandwidth
- reconstruction of pulse by discriminator
- **tr 10%-90% = 300 ps,**
- **BW = 0.35 / tr ~ 0.9 GHz**
- can also use $BW = 0.1 / (t_{50\%} - t_{10\%})$





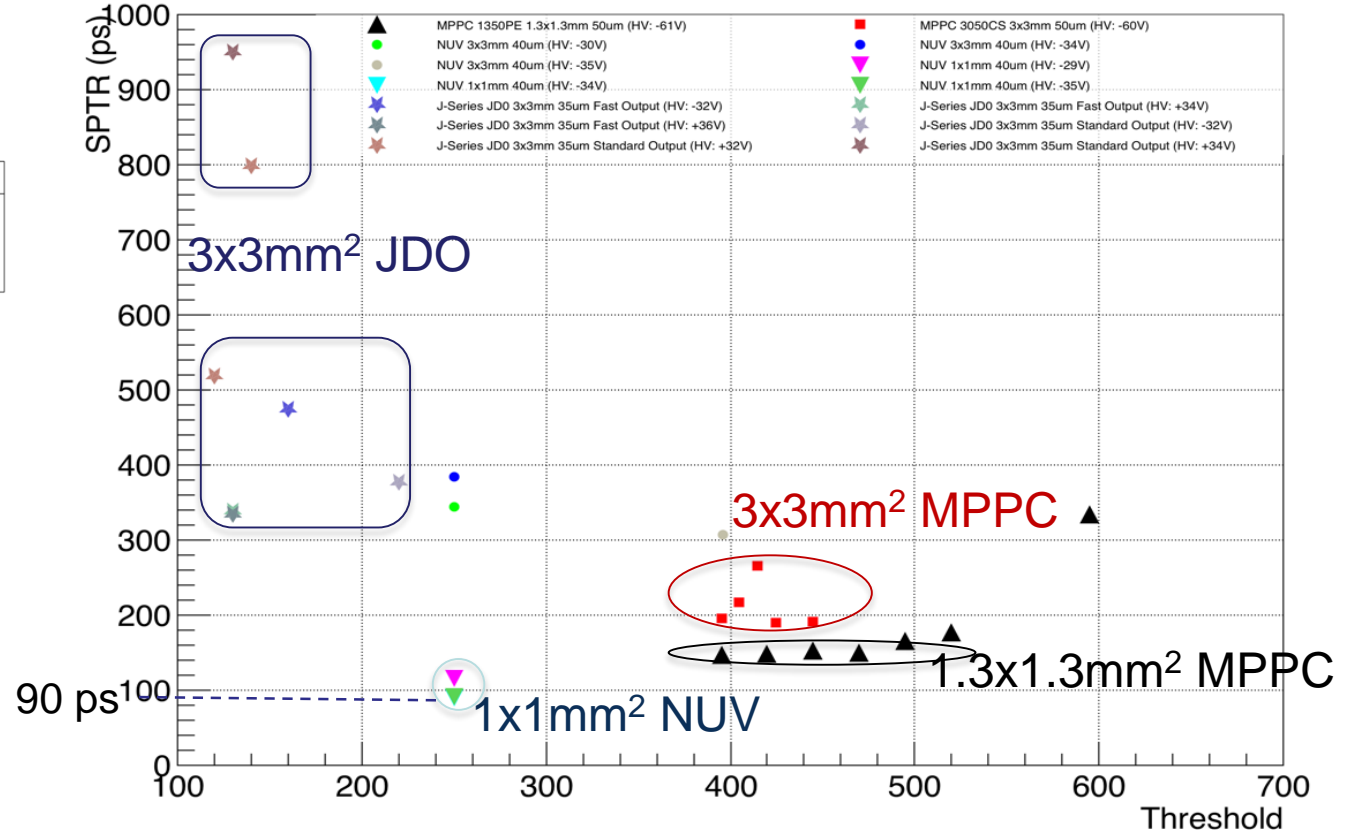
- SPTR : 90 ps FWHM (40 ps rms)



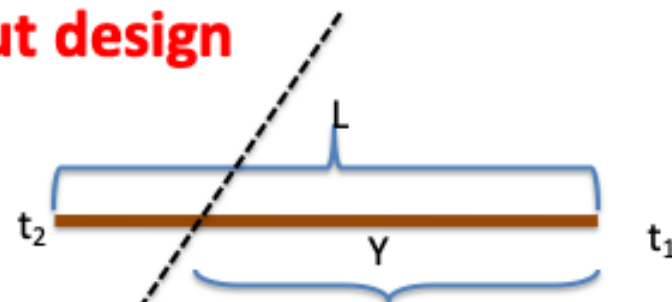
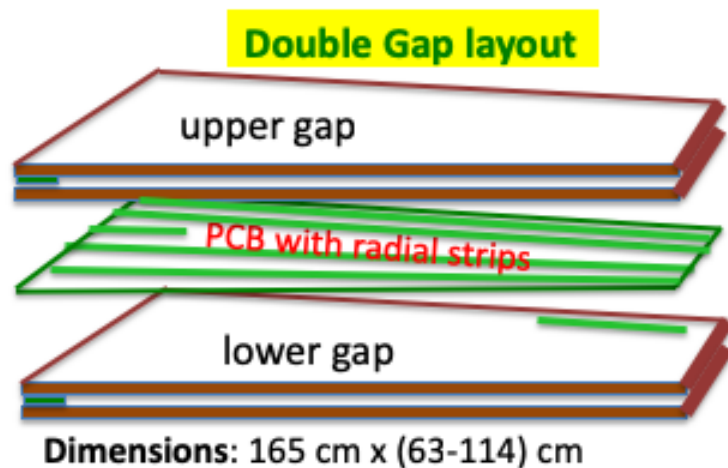
FBK NUV 1x1 mm² : 90.7 ps FWHM

Source : Laser
 SiPM : Various model (FBK, Hamamatsu, Sensl)
 HV : Various value

Petiroc2A SPTR



CMS iRPC readout design

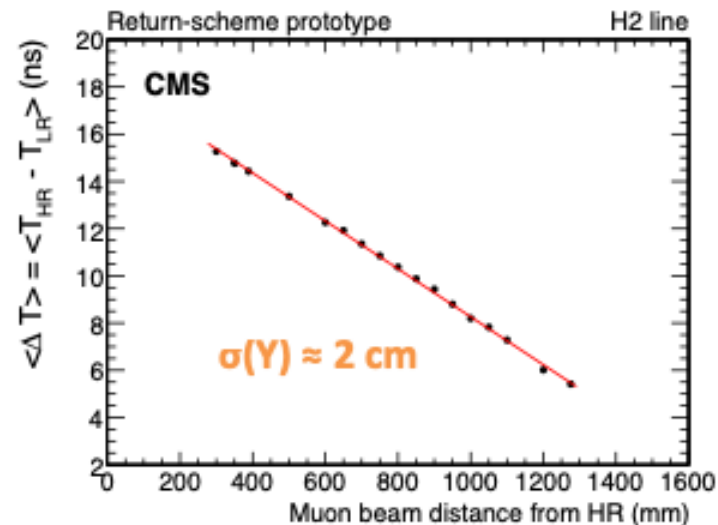
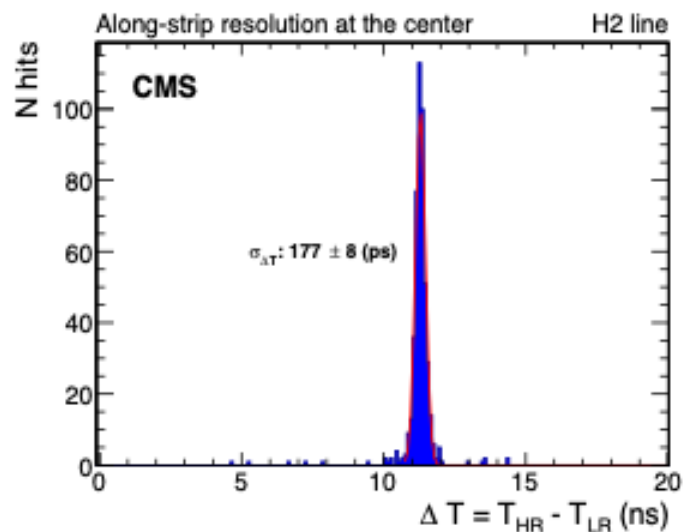


The strips are read out from both ends (2D readout) with good timing FEB.

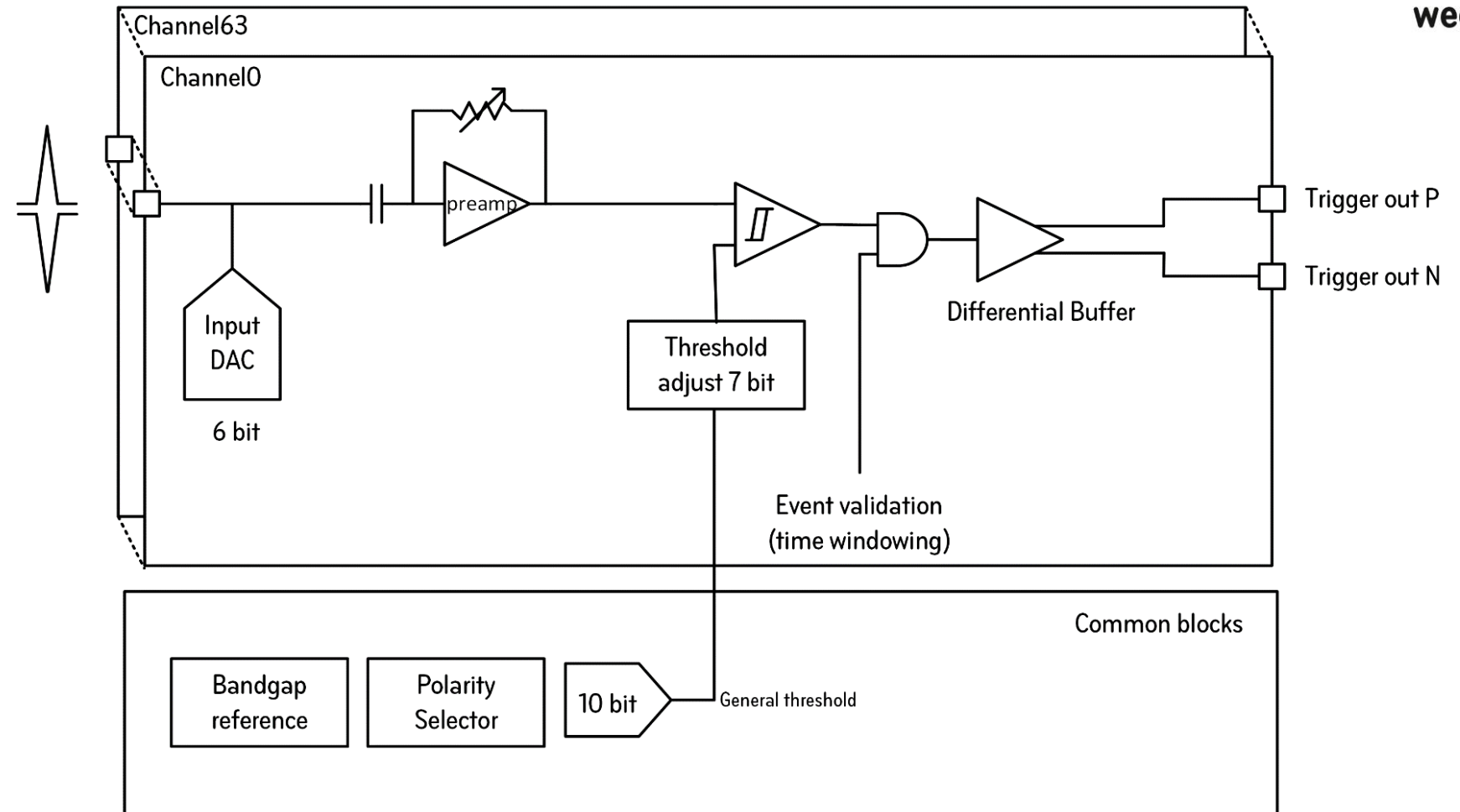
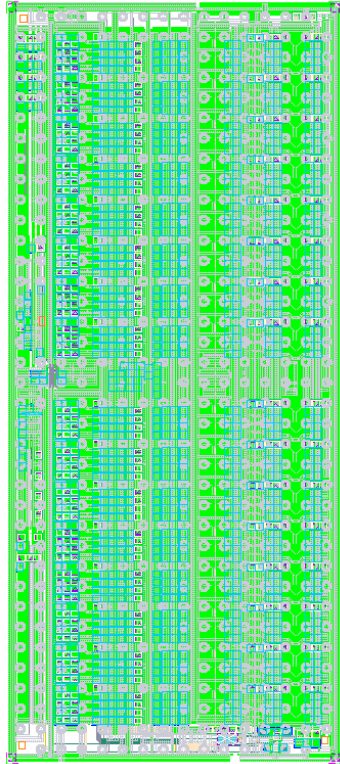
→ Better Y determination

$$Y = L/2 - v \cdot (t_2 - t_1)/2 \rightarrow \sigma(Y) = v \cdot \sigma(T_2 - T_1)/2$$

→ Good absolute timing



SiPM read-out for LIDAR
TSMC 130 nm

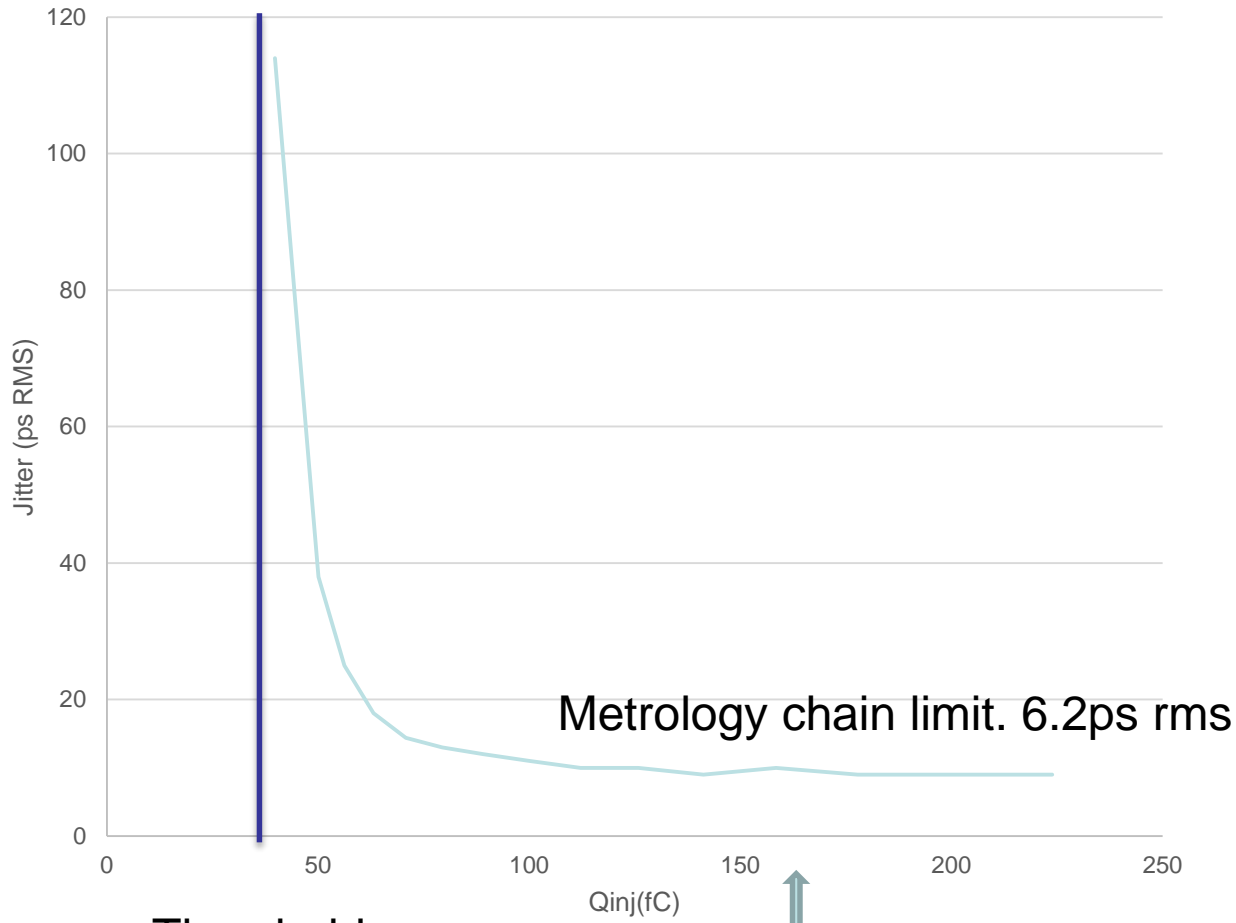


Collaborative design between
Weeroc & Omega
Funding from ATTRACT EU
H2020 Research & Innovation
Program

Detector Read-Out	SiPM, SiPM array
Number of Channels	64
Signal Polarity	Positive or Negative (selectable ASIC-wise)
Sensitivity	Trigger on 1/3 of photo-electron
Timing Resolution	Better than 20 ps FWHM on single photo-electron Better than 5ns double-peak separation on single photo-electron
Dynamic Range	Over 100MHz photon counting rate
Packaging & Dimension	BGA 20x20 mm ² Flip-Chip low inductance packaging technology
Power Consumption	210mW – Supply voltage : 1.2 V
Inputs	64 analogue inputs with independent SiPM HV adjustments
Outputs	64 low-common-mode LVDS triggers (CLPS) – compatible with CERN picoTDC and all LVDS FPGA I/Os
Internal Programmable Features (I ² C)	64 HV adjustment for SiPM (64 x 6 bit), trigger threshold programming (10bits), 64 x 7 bit channel-wise threshold adjustment, ASIC-wise polarity selector, preamp pole-zero cancellation adjustment, individual trigger masking and cell powering.



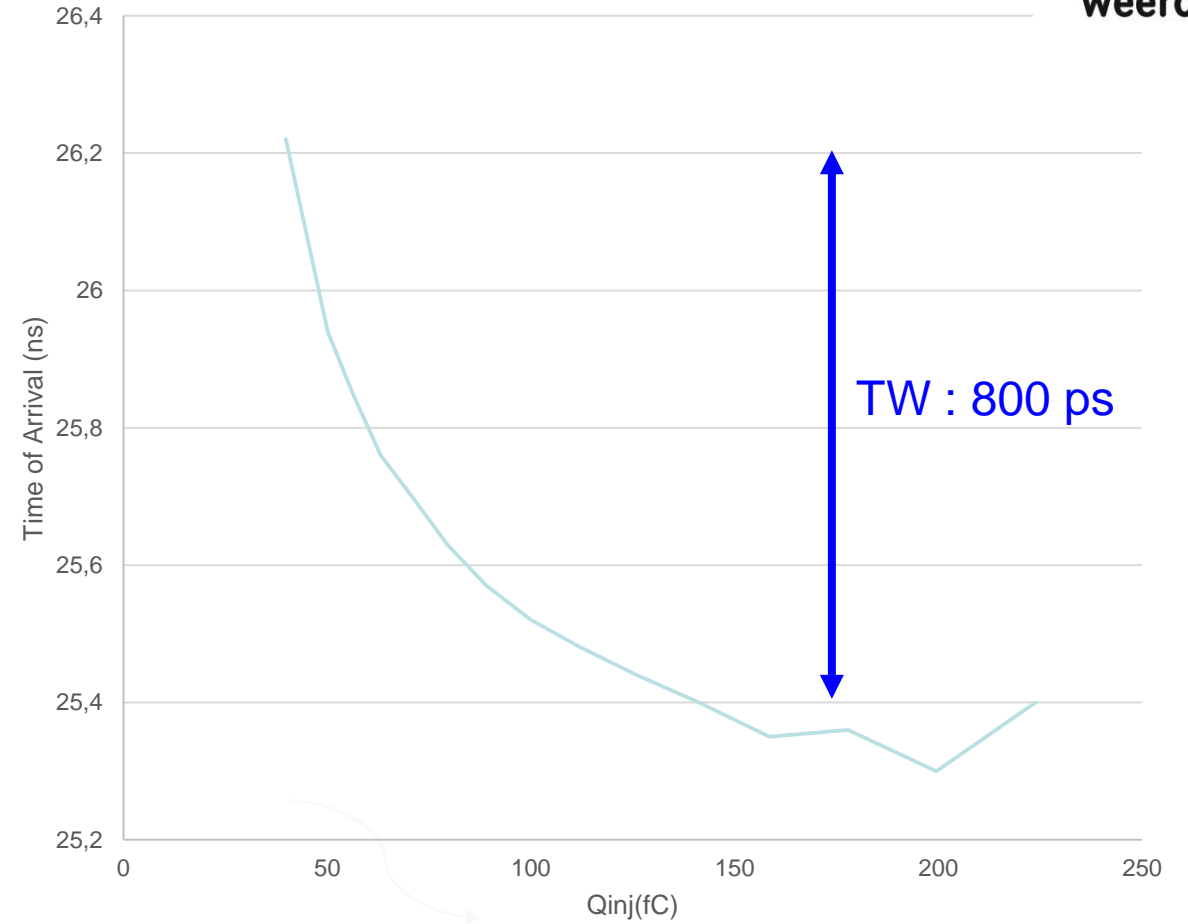
Jitter - Threshold 1/4 Photoelectron (40fC)



Threshold:
40 fC

1 photoelectron - Gain 10^6

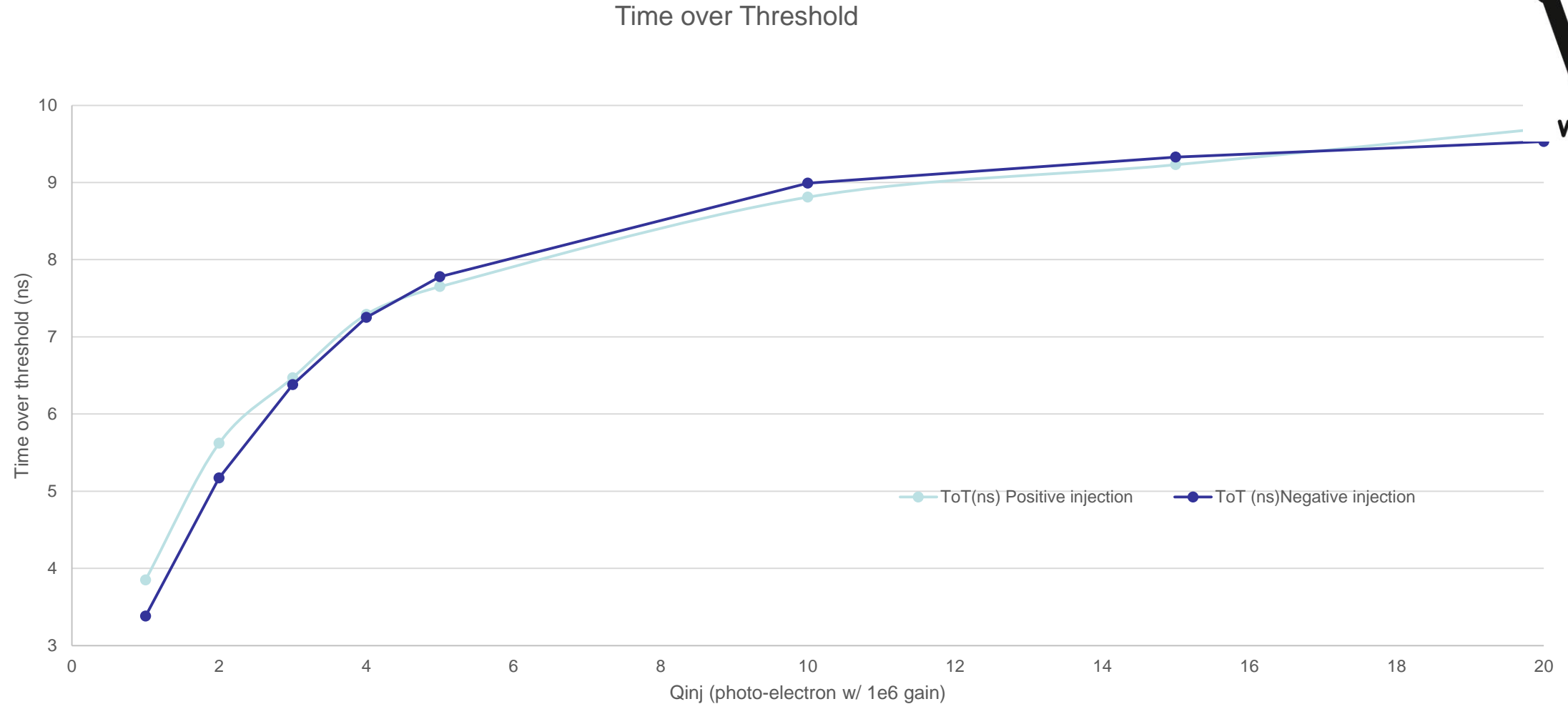
Timewalk - Threshold 1/4 Photoelectron (40fC)



TW : 800 ps



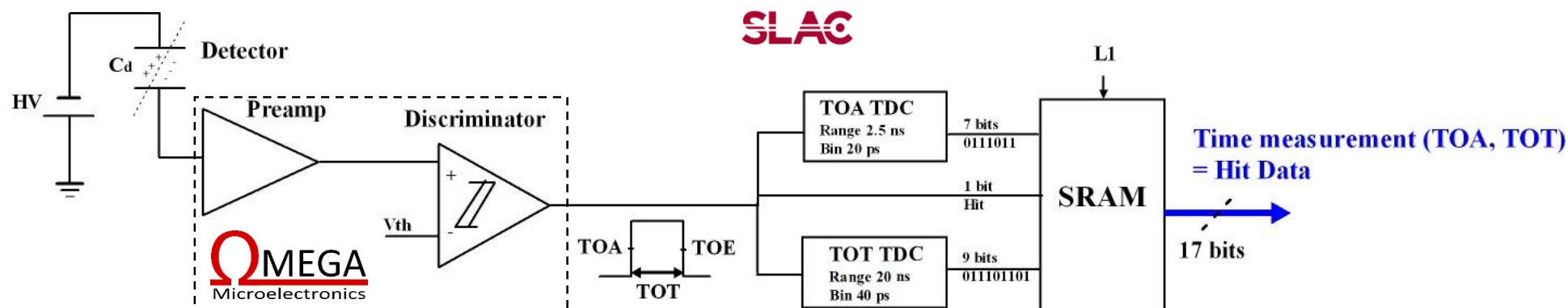
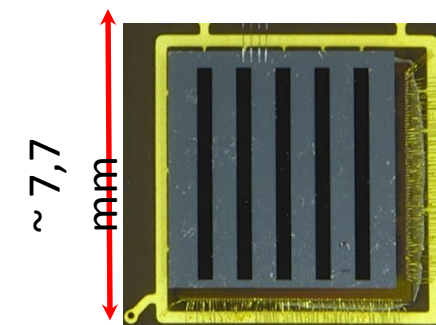
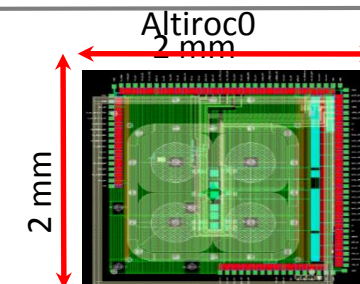
weeroc



Trade-off between double peak separation (see consecutive photons) and time over threshold. Tuneable. Optimized for double-peak separation in that measurement (3ns separation measured)

ALTIROC : ATLAS LGAD ReadOut Chip for HGTD

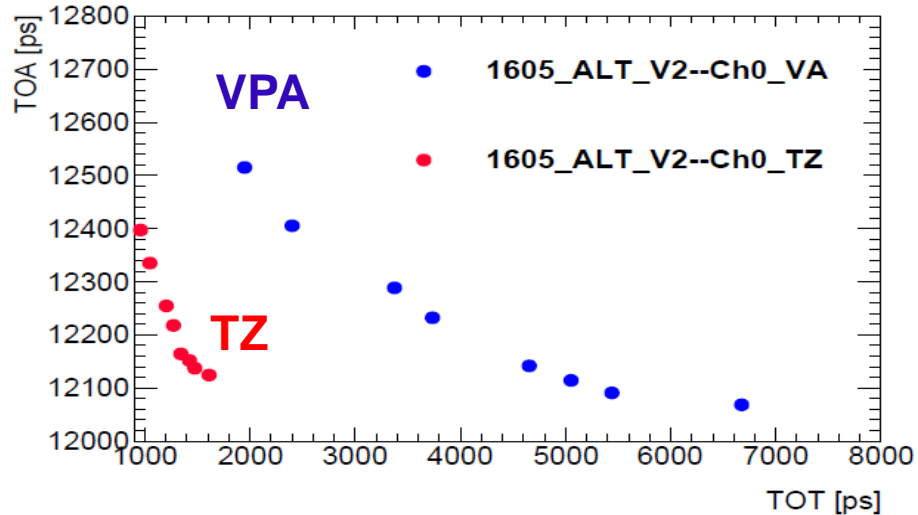
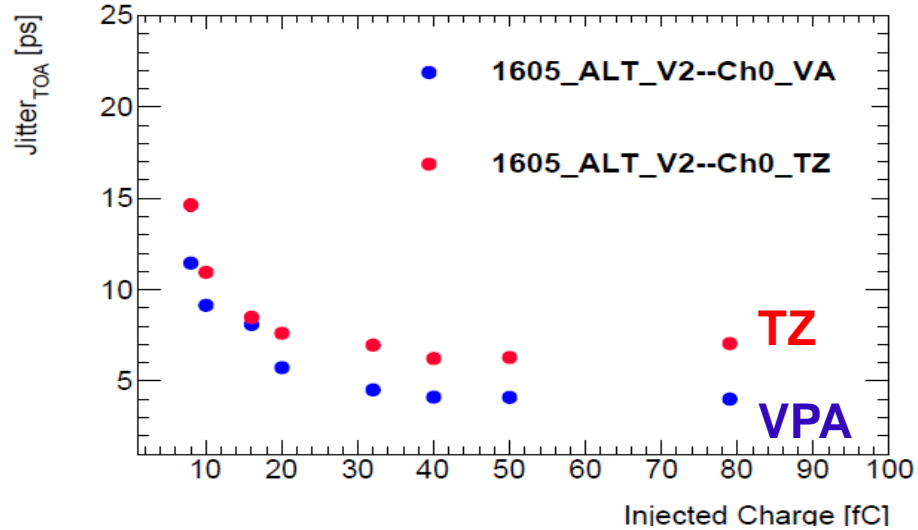
- **ALTIROC0 (2017)** : contains only PA + discriminator – for 2x2 1x1 mm² sensors
 - 4 channels VPA and 4 channels TZ analog readout optimized for $C_d=2\text{pF}$
 - Bandwidth tunable (0.3-0.8 GHz)
 - Power : 2 mW/ch TSMC 130 nm
- **ALTIROC1 (2018)** : 5x5 complete readout channels (PA, discri, TDC, SRAM) to readout 1.3 x 1.3 mm² LGAD pixels , 15 channels with VPA, 10 with Transimpedance amplifier (TZ)
- **ALTIROC2 (2021)** : 15x15 final size and fonctionnality



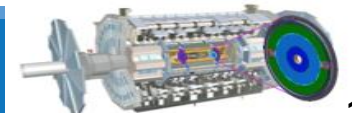
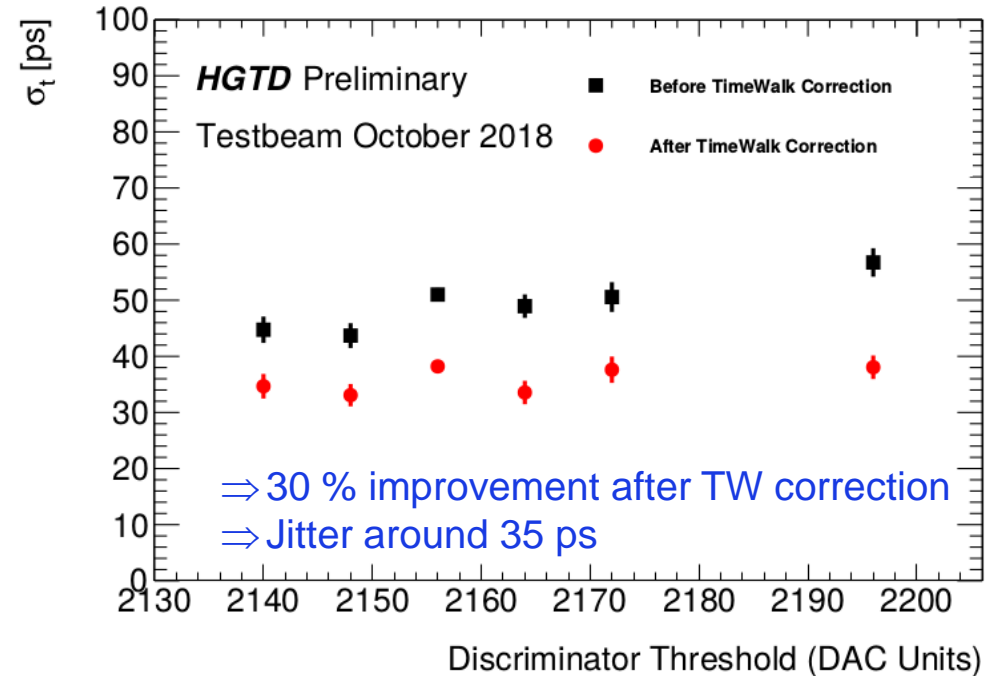
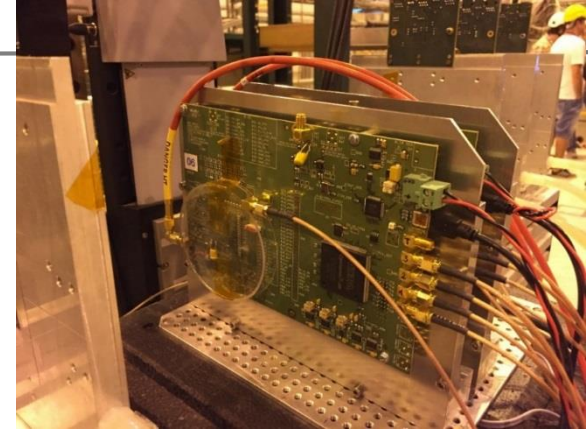
ATLAS
HGTD

ALTIROCO measurements

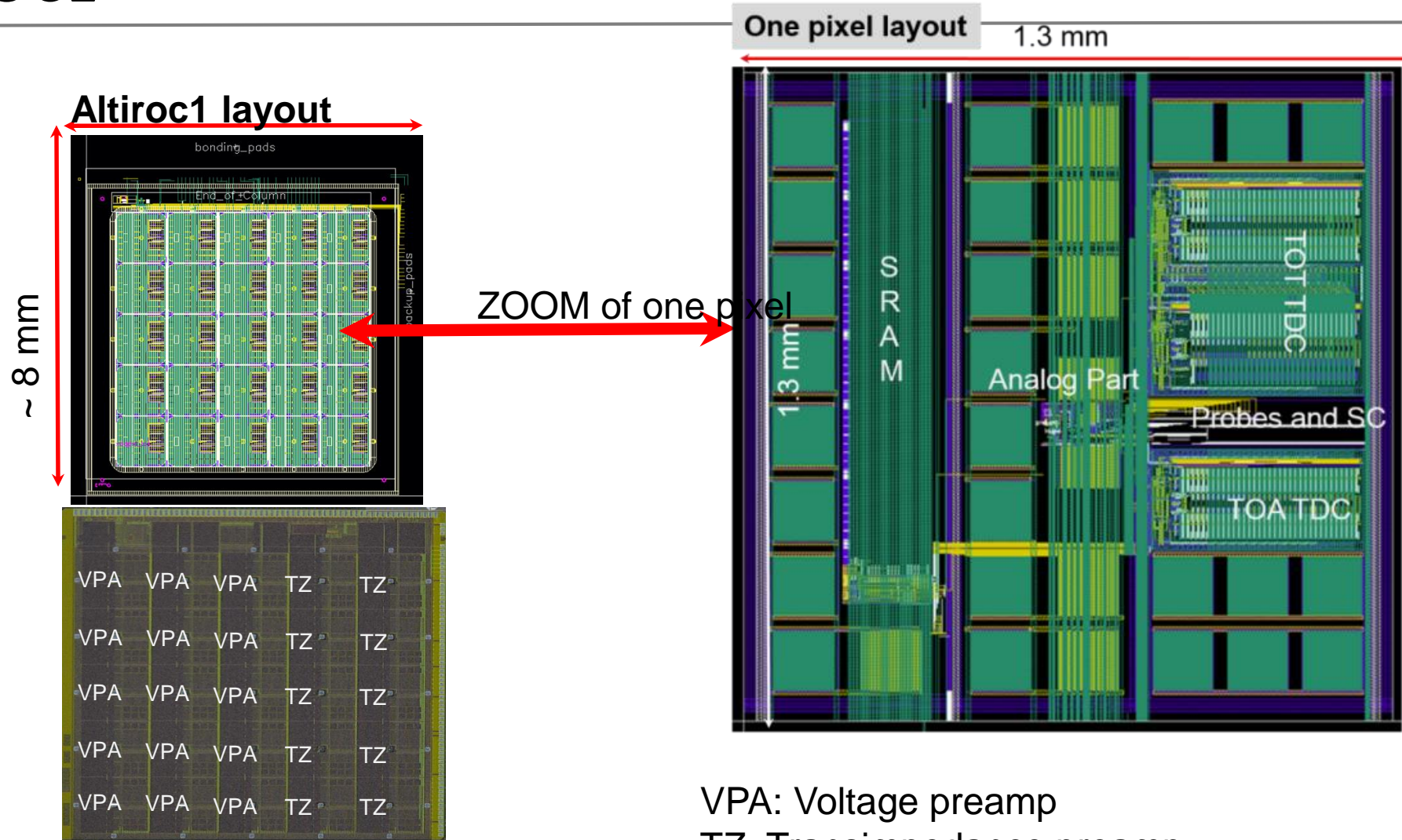
- Testbench (left) and testbeam (right) measurements



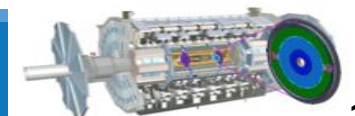
- ALTIROCO_V2
- Time resolution of a 2x2 x1x1 mm² LGAD array bump bonded on an Altiroc0 ASIC as a function of the disci threshold (DAC Units) before (black points) and after TW correction (red points)



ALTIROC1



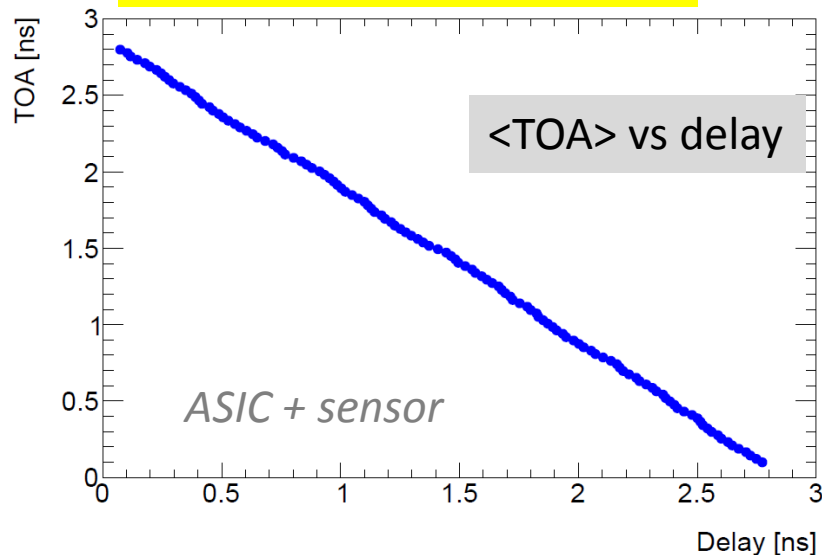
VPA: Voltage preamp
TZ: Transimpedance preamp



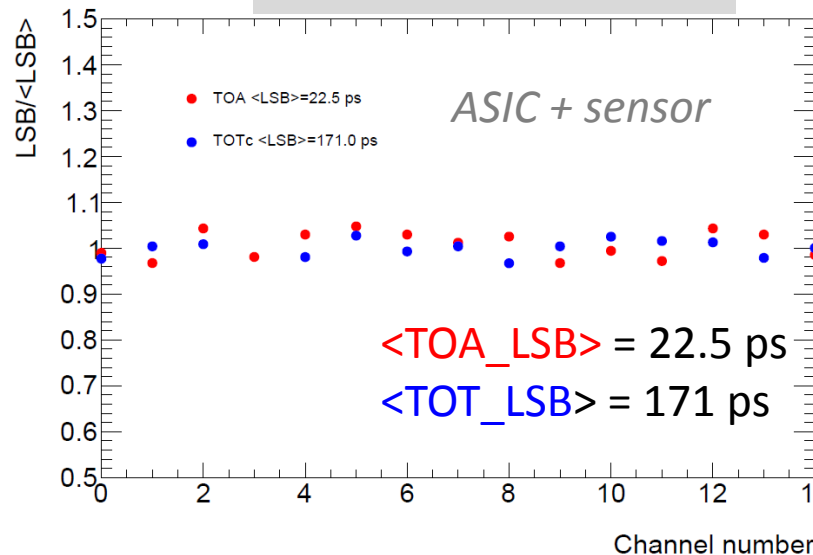
ALTIROC1_V2 - TDC performance

Specifications:

TOA: 20 ps \pm 10%, range 2.5 ns

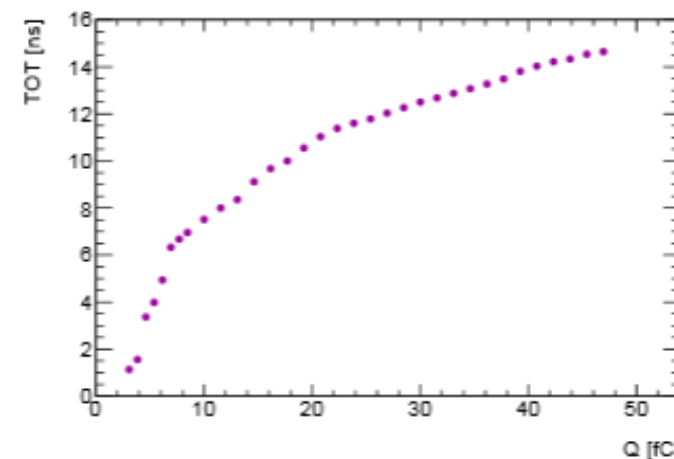


LSB /<LSB> vs channel



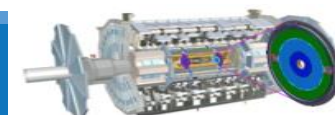
Specifications:

TOT: 160 ps \pm 10%, range 20 ns



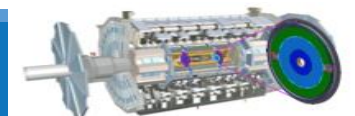
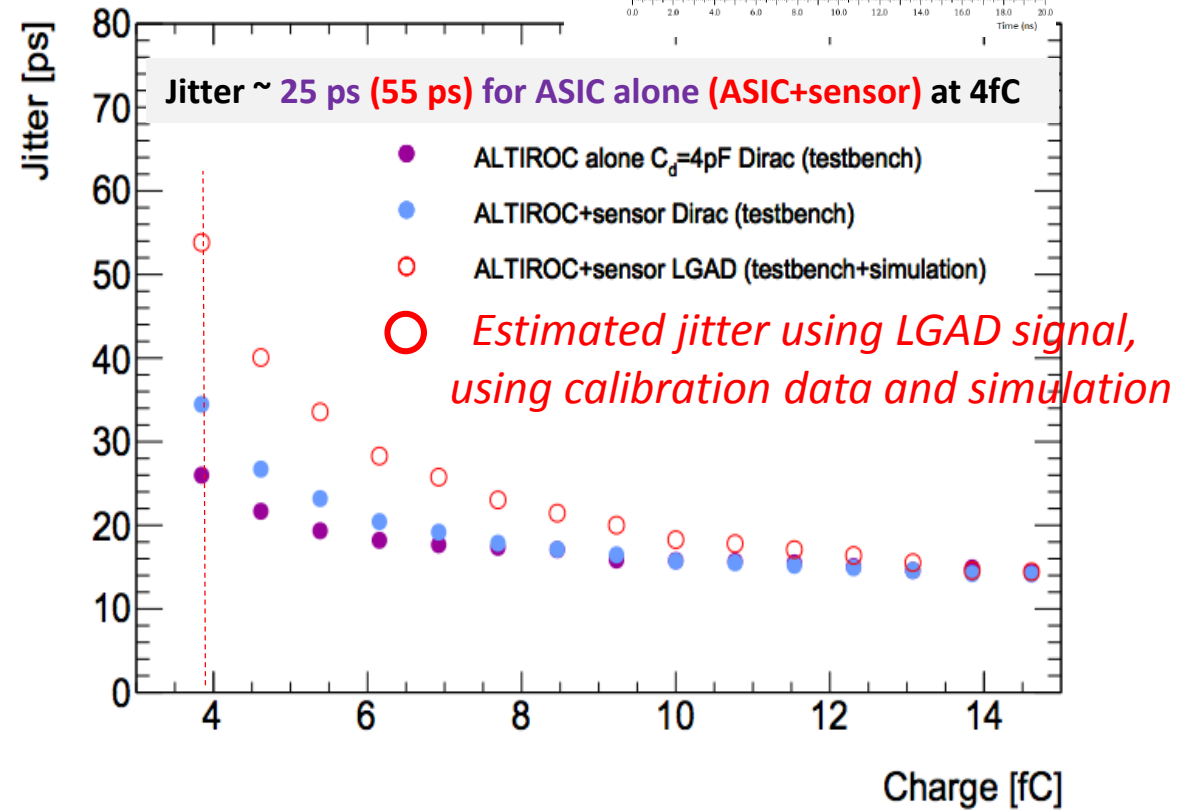
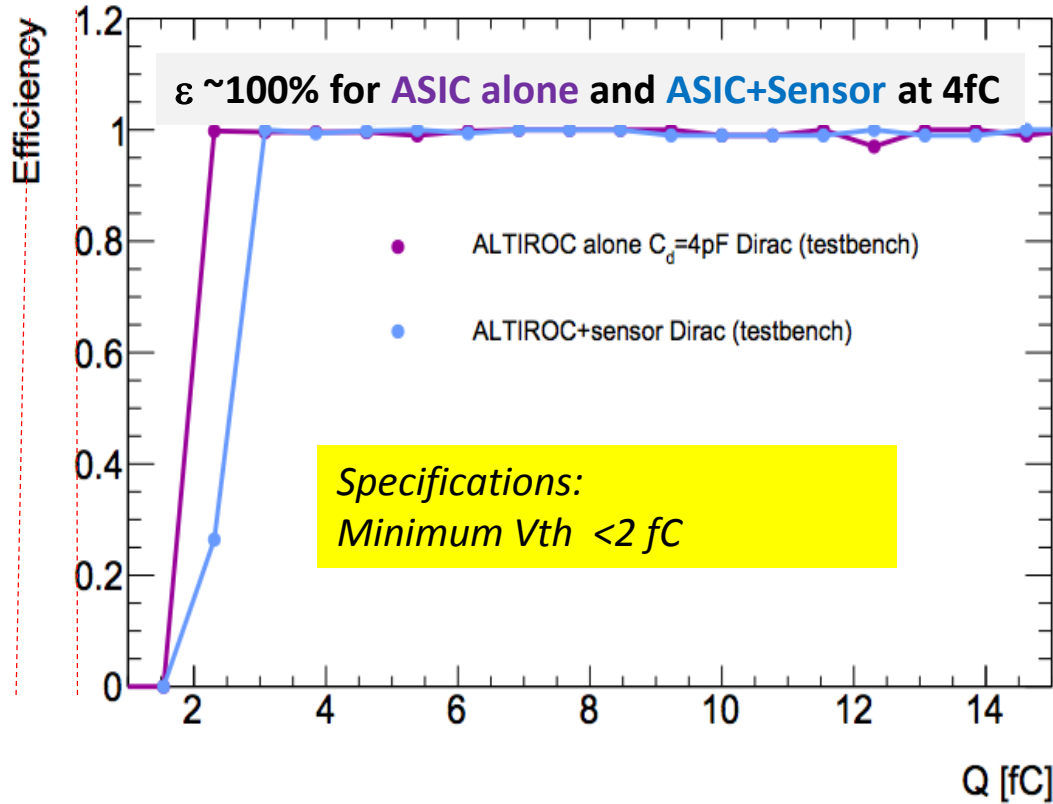
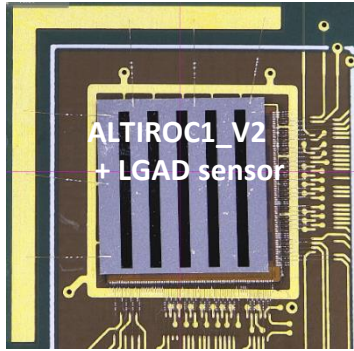
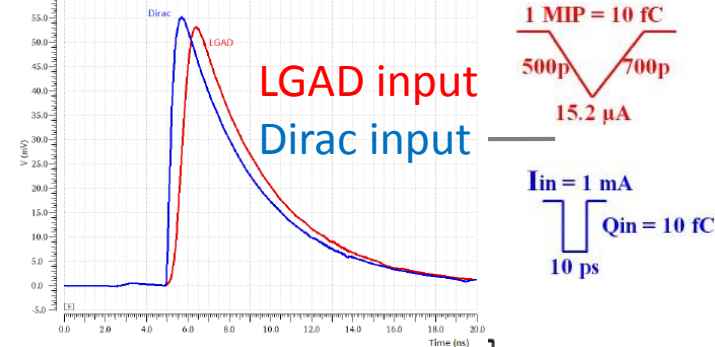
- **TOA_LSB** and **TOT_LSB** can be adjusted to **20 ps** and to **160 ps** (respectively) using per channel Slow Control parameters
- Some of the DLLs don't lock properly => use of external R to set control voltages of the TDC
- **<TOA> vs delay**: Small discontinuities due to LSB bin size that can be calibrated with Random Programmable Generator

=> **Altiroc1_V3**: integrates a Random Programmable Generator



ALTIROC1_V2- performance at system level

out_preamplifier simulation



ATLAS
HGTD

Overall chip divided in two symmetrical parts

- 1 half is made of:
 - 39 channels: 18 ch, CM0, Calib, CM1, 18 ch (78 channels in total)
 - Bandgap, voltage reference close to the edge
 - Bias, ADC reference, Master TDC in the middle
 - Main digital block and 3 differential outputs (2x Trigger, 1x Data)

Measurements

- Charge
 - ADC (AGH): peak measurement, 10 bits @ 40 MHz, dynamic range defined by preamplifier gain
 - TDC (IRFU): TOT (Time over Threshold), 12 bits (LSB = 50ps)
 - ADC: 0.4 fC resolution. TOT: 2.5 fC resolution
- Time
 - TDC (IRFU): TOA (Time of Arrival), 10 bits (LSB = 25ps)

Two data flows

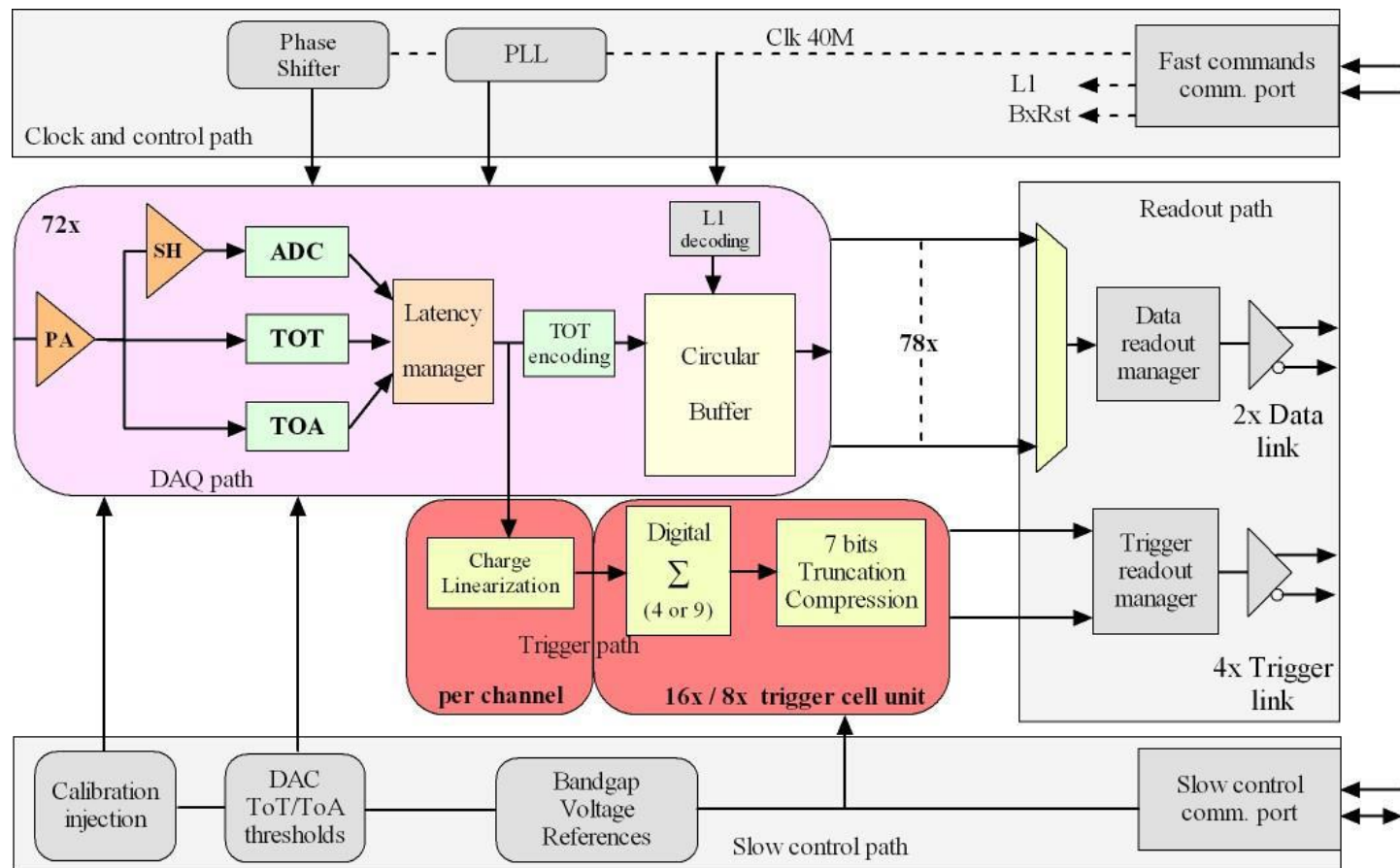
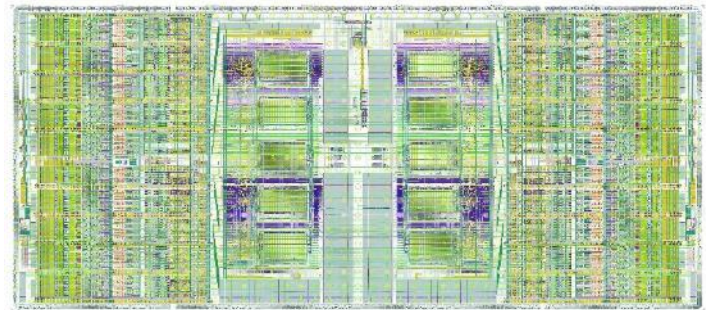
- DAQ path
 - 512 depth DRAM (CERN), circular buffer
 - Store the ADC, TOT and TOA data
 - 2 DAQ 1.28 Gbps links
- Trigger path
 - Sum of 4 (9) channels, linearization, compression over 7 bits
 - 4 Trigger 1.28 Gbps links

Control

- Fast commands
 - 320 MHz clock and 320 MHz commands
 - A 40 MHz extracted, 5 implemented fast commands
- I2C protocol for slow control

Ancillary blocks

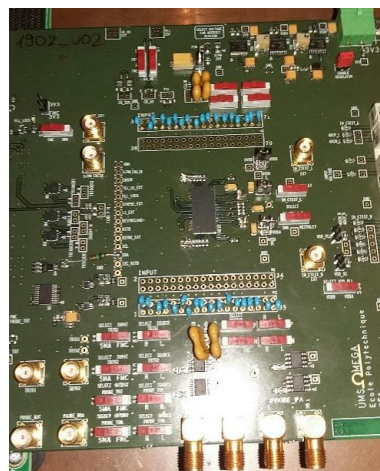
- Bandgap (CERN)
- 10-bits DAC for reference setting
- 11-bits Calibration DAC for characterization and calibration
- PLL (IRFU)
- Adjustable phase for mixed domain



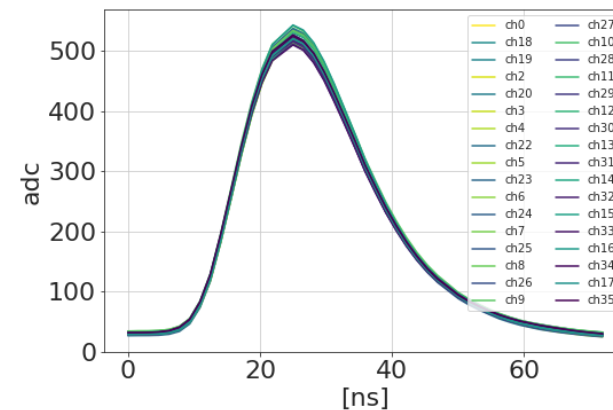
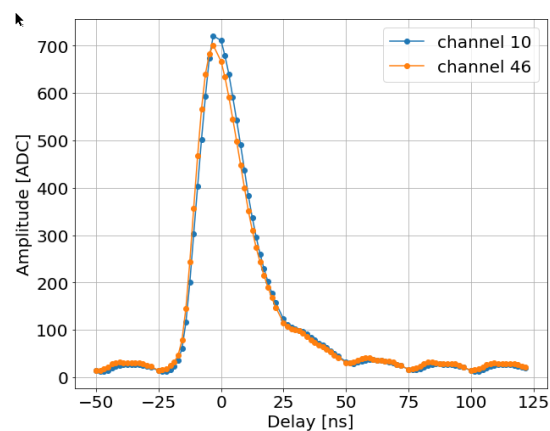
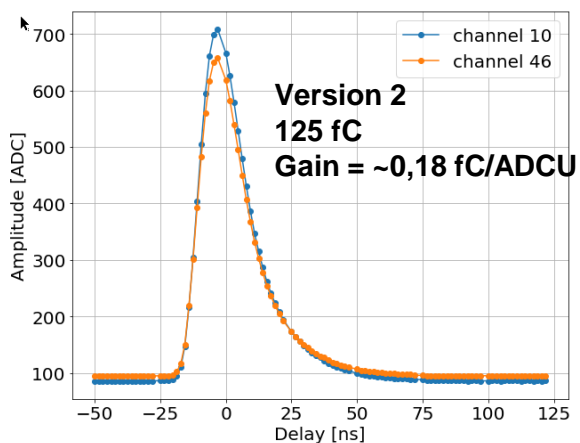
Flip-Chip on mezzanine



HD BGA board

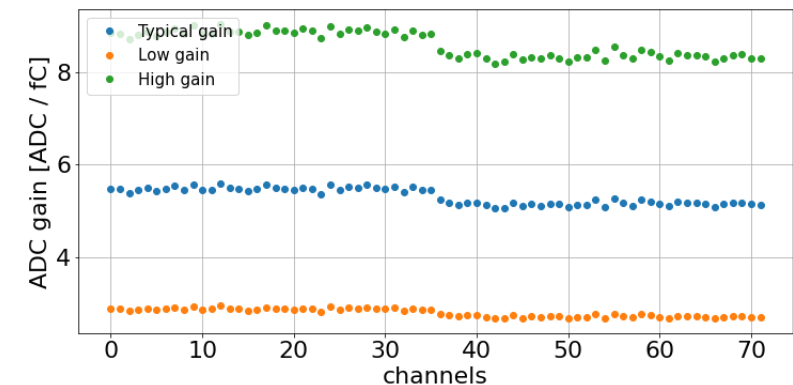
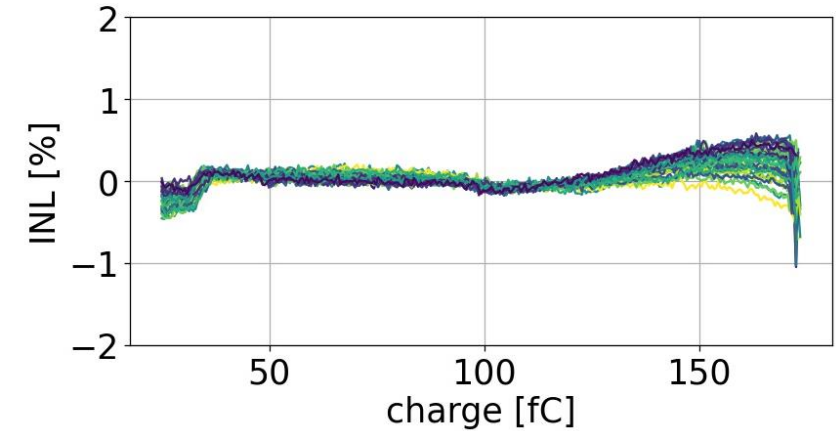
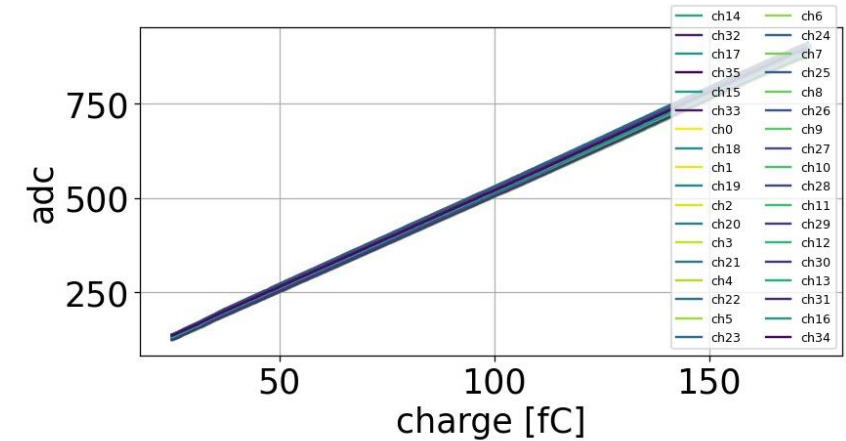
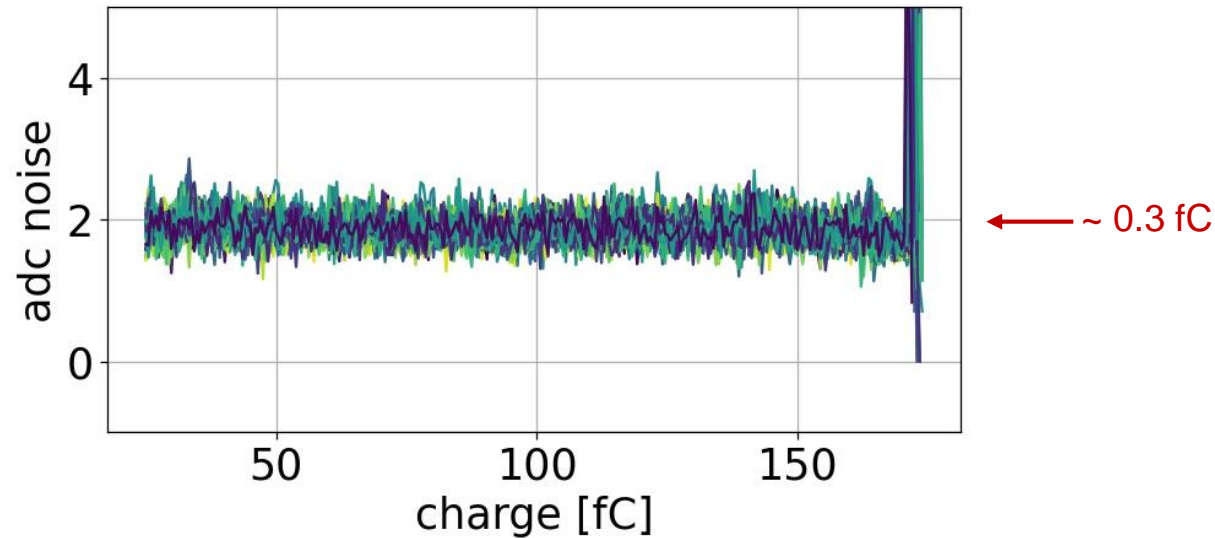


HD BGA on mezzanine



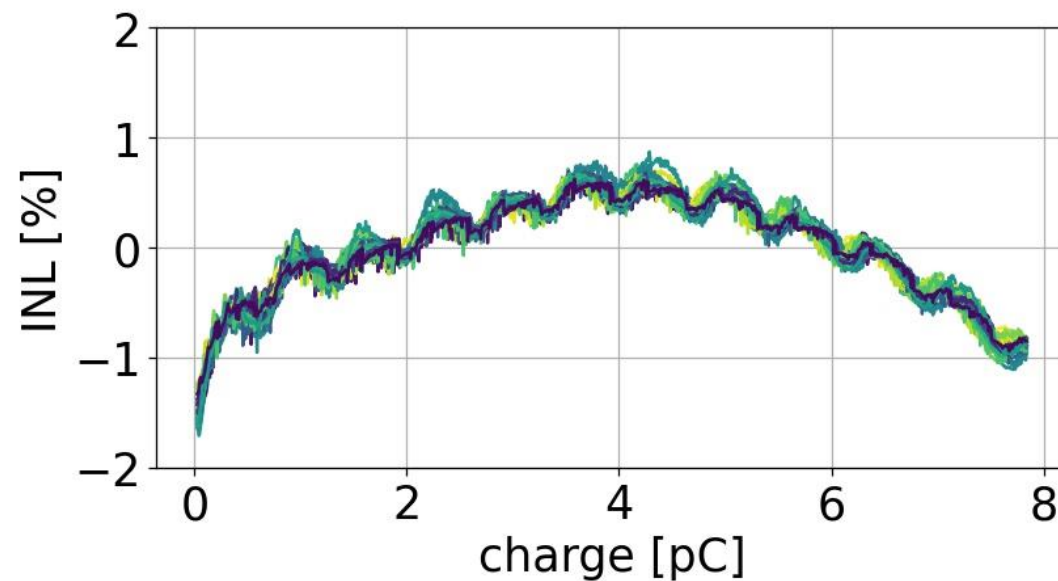
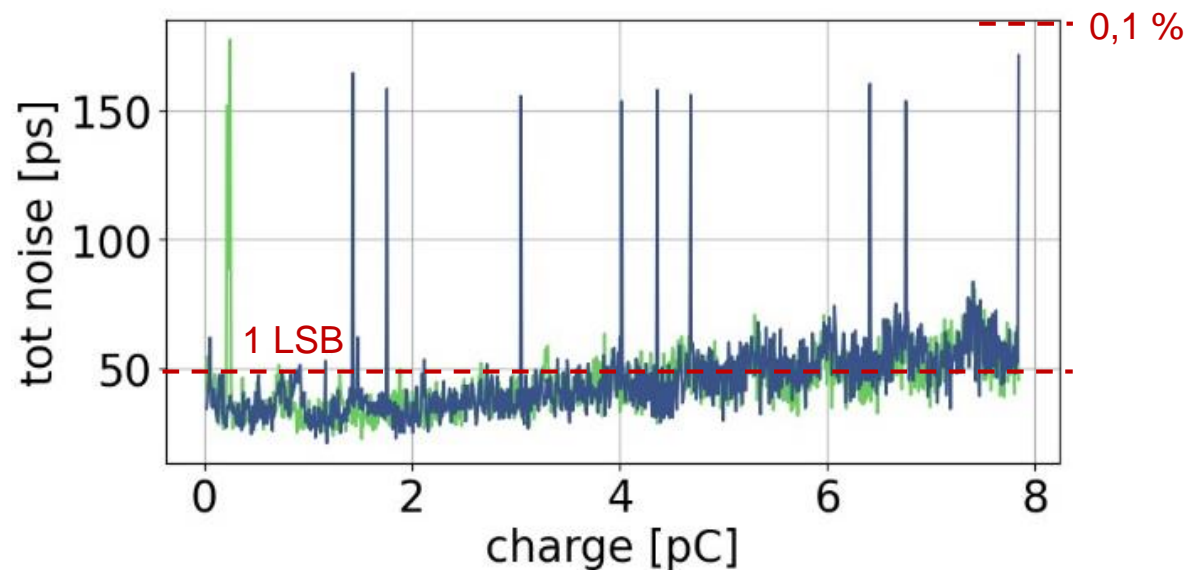
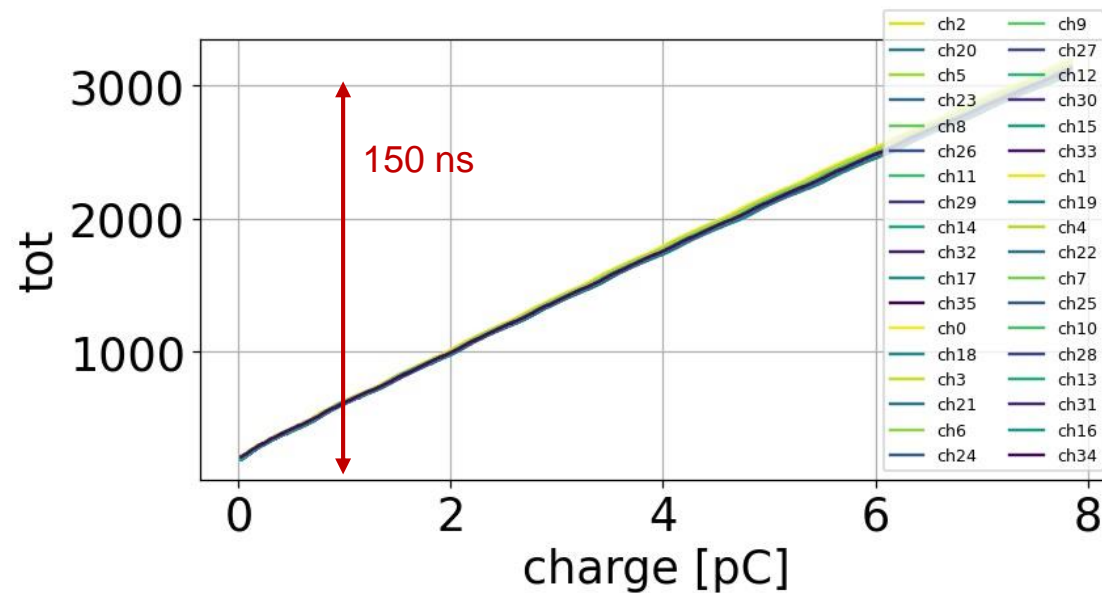
- Separates effects from the BGA substrate and PCB
- Rising time (10-90 %): ~ 15 ns
- Falling time (10-90 %): ~ 30 ns, < 20 % at BX+1
- Good uniformity over the channels
- Digital 40 MHz clock coupling on the analog signal on the HD BGA board: digital noise (slide 11)

- Two 10b-DAC to globally set the pedestal to a wanted level
- 5b-DAC to reduce dispersion per channel
 - From ~ 100 ADCu dispersion to ~ 5 ADCu
- Good linearity within $\pm 0.5\%$
 - 1.6 fC (~ 1 MIP) linearity for the typical gain
- ~ 0.3 fC resolution with 50 pF input capacitor



Charge measurement from TOT when preamplifier saturates

- 160 fC to 10 pC (for the typical preamplifier gain)
 - 12 bits over 200 ns
 - 50 ps binning
- Linearity
 - < 2% linearity
 - Better with input capacitor (as expected)
 - Small residual wiggles on TOT due to digital noise on preamplifier input
- Resolution around the LSB (~ 50 ps)
 - Some peaks due to outliers (understood and fixed)



Noise

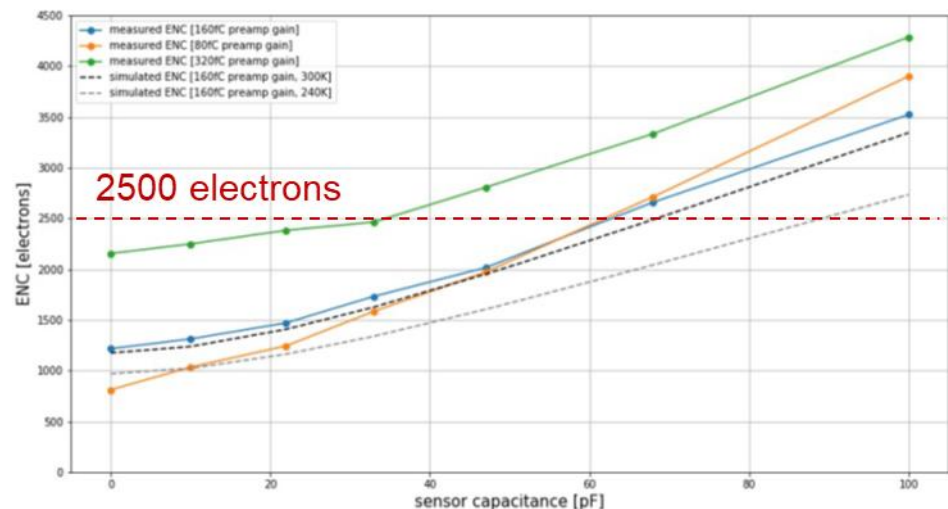
- Measured noise with 50 pF input cap = **0.3 fC** (~ 2000 electrons) (0.7 nV / $\sqrt{\text{Hz}}$)
- Very low correlated noise contribution: ~ **0.1**
- Coherent noise extracted by comparing direct and alternate sums on n channels (n = 72):

$$DS = \sum ped[i]; AS = \sum (-1^i) ped[i]$$

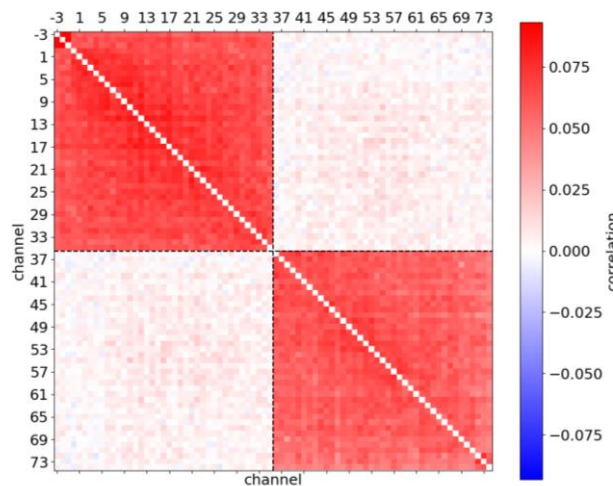
- Incoherent noise $IN = rms(AS)/\sqrt{n}$
- Coherent noise $CN = \sqrt{var(DS) - var(AS)}/n$

	0 pF Cdet	47 pF Cdet	68 pF Cdet
High gain ENC	900 electrons	2000 electrons	2750 electrons
Typical gain ENC	1250 electrons	2000 electrons	2700 electrons
Low gain ENC	2200 electrons	2800 electrons	3400 electrons
TOA FOM ⁽¹⁾	NA	2.5 ns/fC (FlipChip) 3 ns/fC (BGA)	3 ns/fC (FlipChip)
TOA noise floor ⁽¹⁾	20 ps	25 ps (FlipChip) 25 ps (BGA)	25 ps (FlipChip)
TOA Time-Walk	0.8 ns (FlipChip) 4 ns (BGA)	2.5 ns (FlipChip) 6.5 ns (BGA)	4 ns (FlipChip)

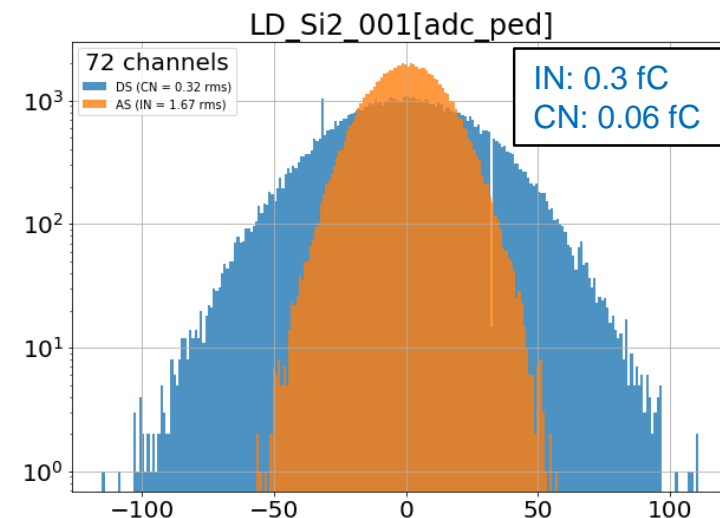
Equivalent Noise Charge wrt. sensor capacitance



Correlation matrix

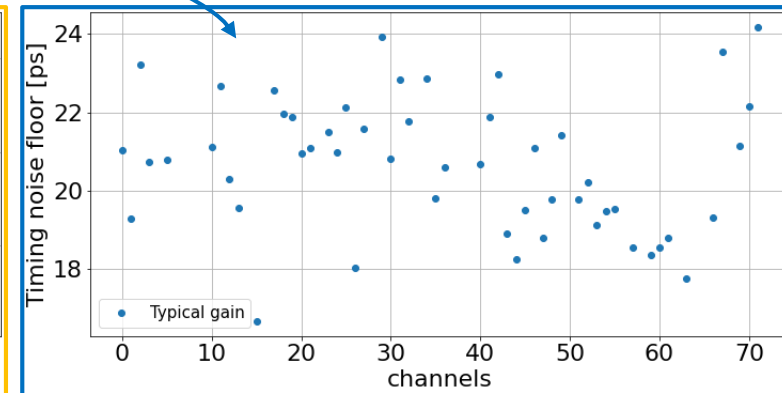
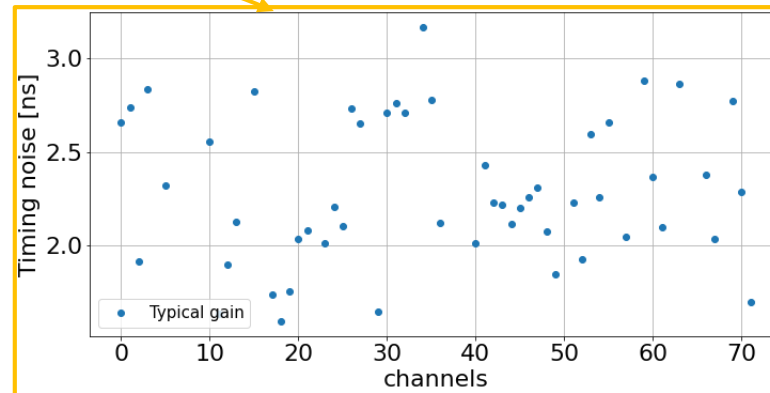
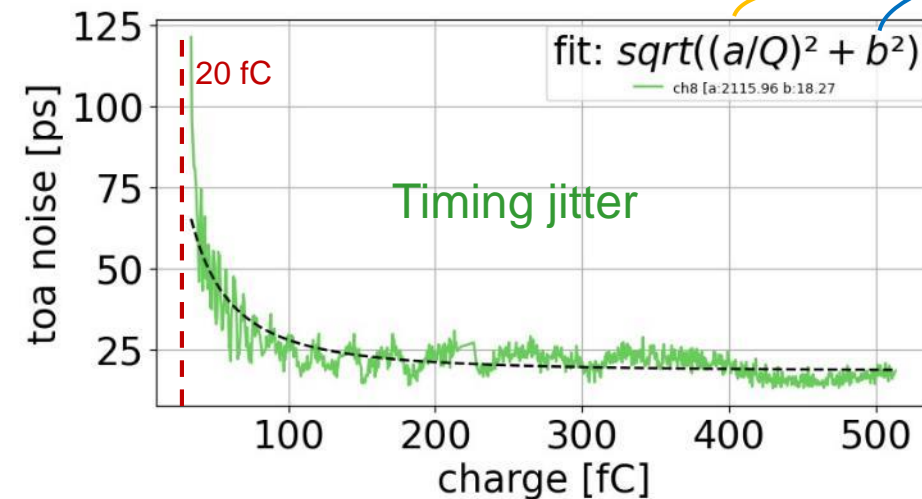
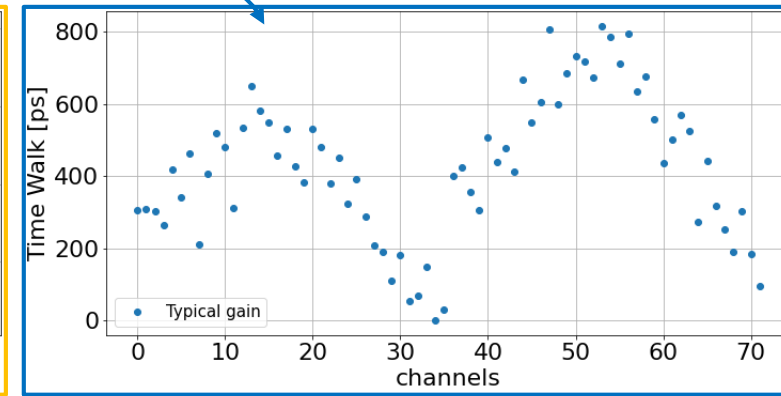
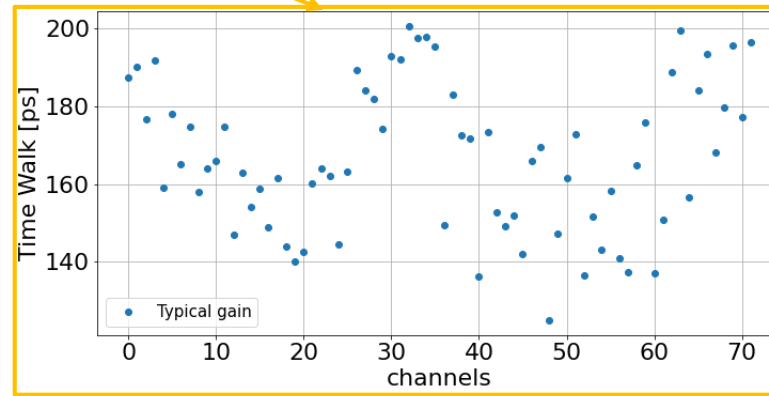
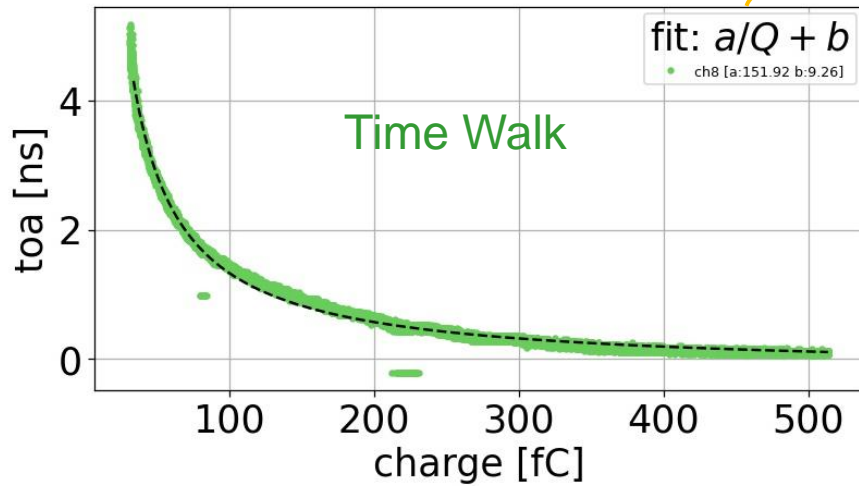


Coherent vs. incoherent noise

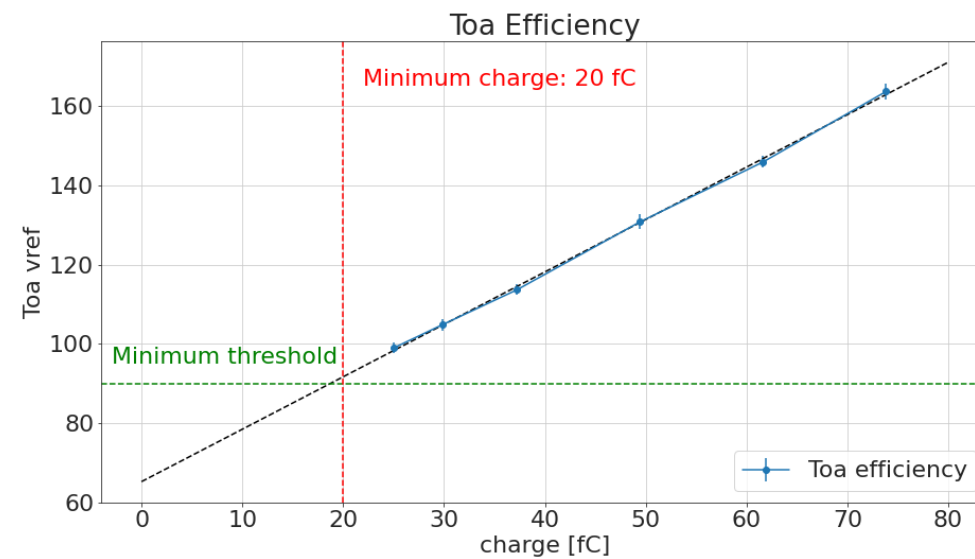
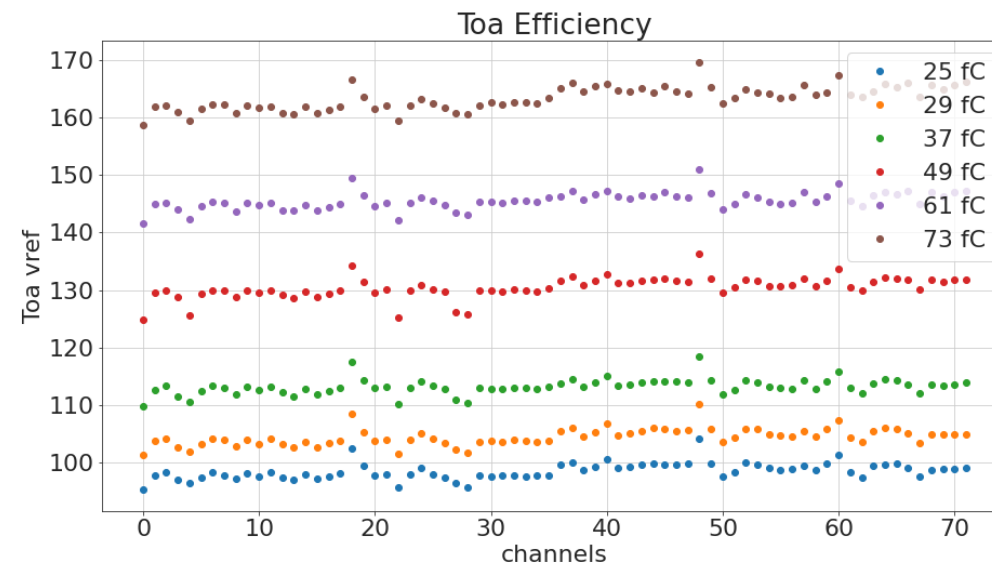
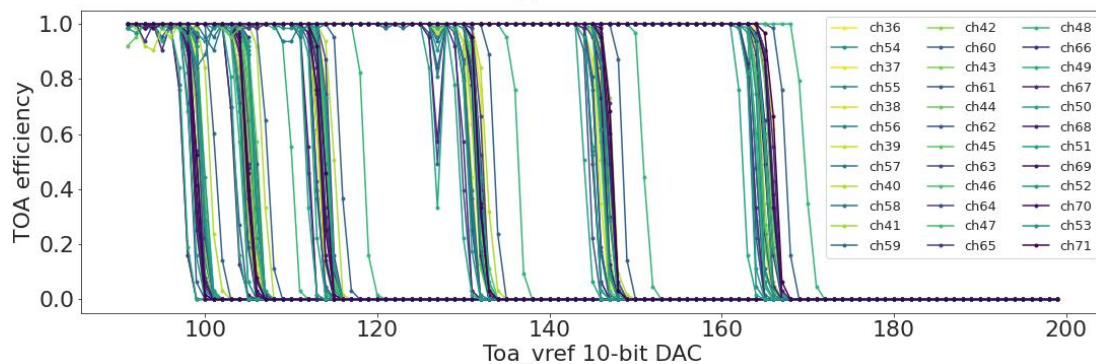
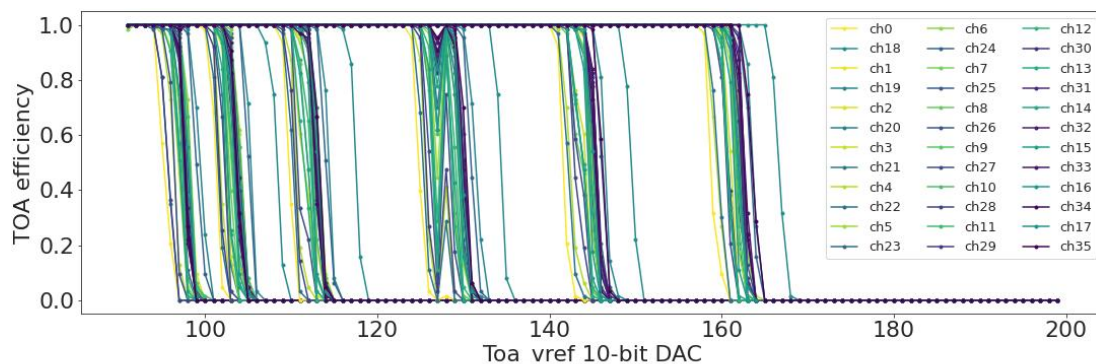


Timing performance

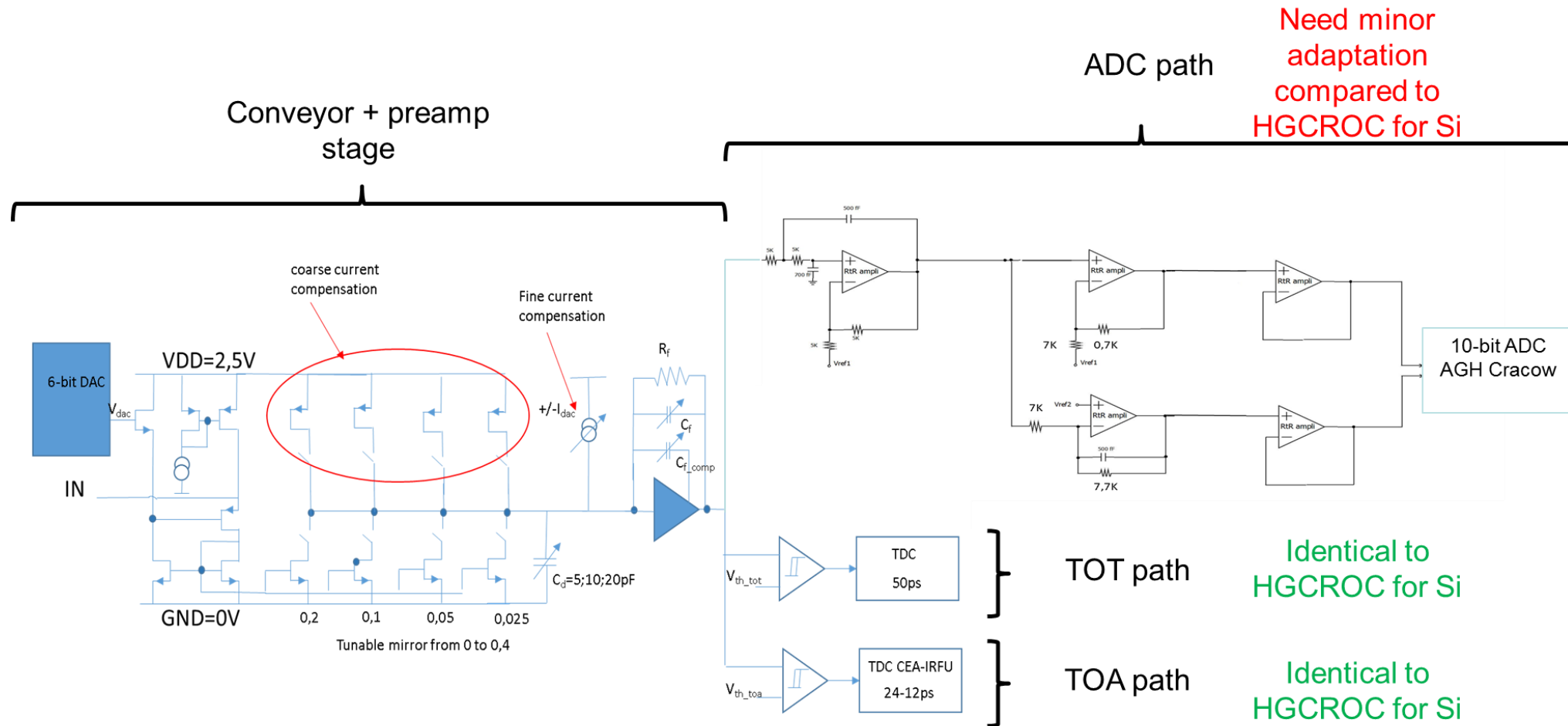
- Minimum Charge providing a TOA measurement is 20 fC, limited by the digital coupling
- $Time\ Walk = \frac{170 [ps]}{Q [fC]} + 400 [ps]$: 2.5 ns w/o detector cap., ~ 5 ns with 50 pF input capacitor
- $Jitter = \frac{2[ns]}{Q[fC]} (+) 22 [ps]$



- S-curves show the ToA efficiency as a function of the charge
- Minimum charge providing ToA events is 20 fC
 - Limited by the digital coupling

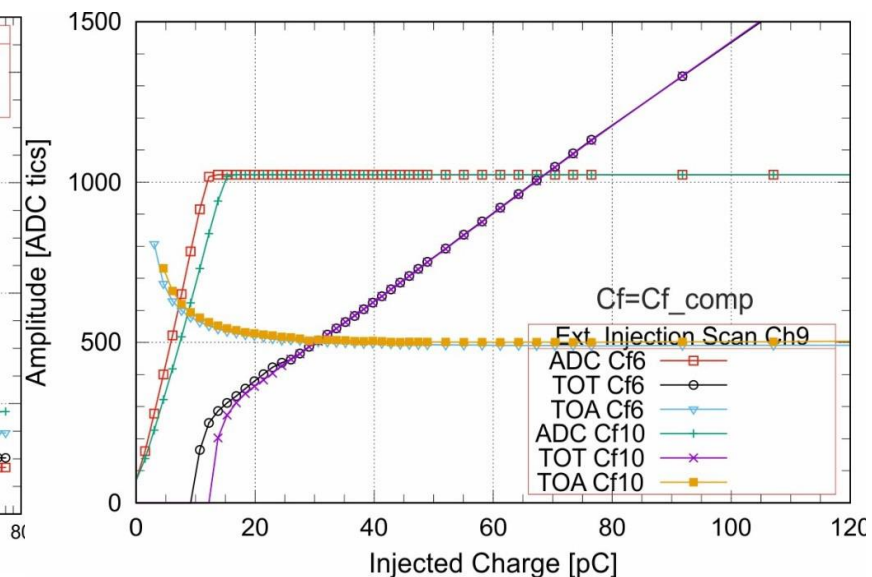
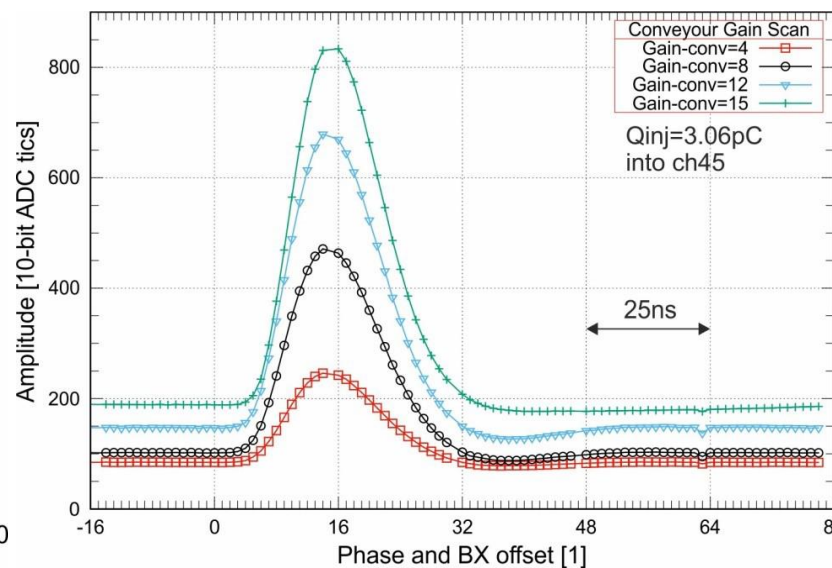
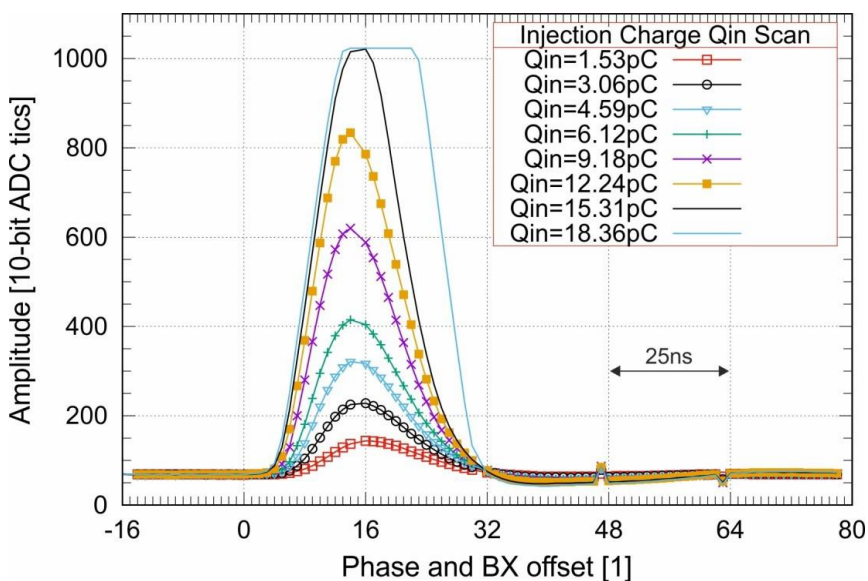
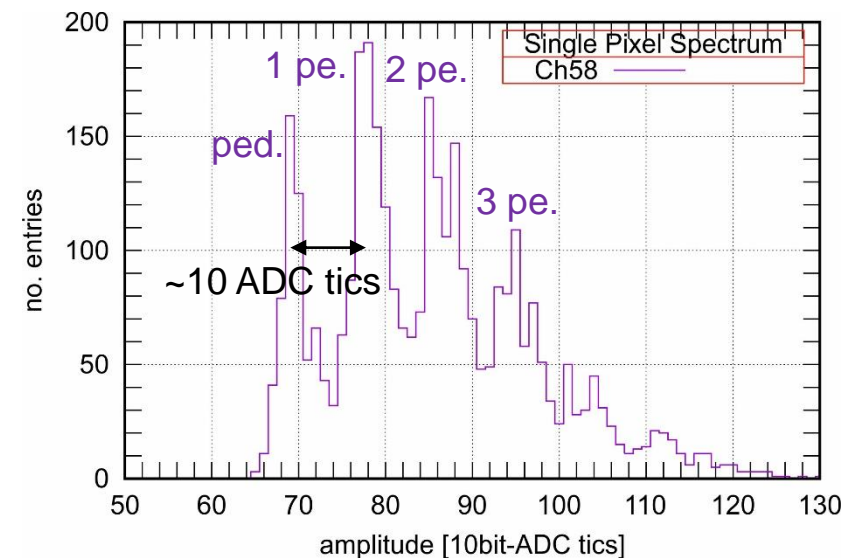


- H2GCROC2 (SiPM version) = HGCROC2 + input current conveyor
 - Heidelberg university design
- 2.5 V input stage for overvoltage adjustment



H2GCROC2 measurements:

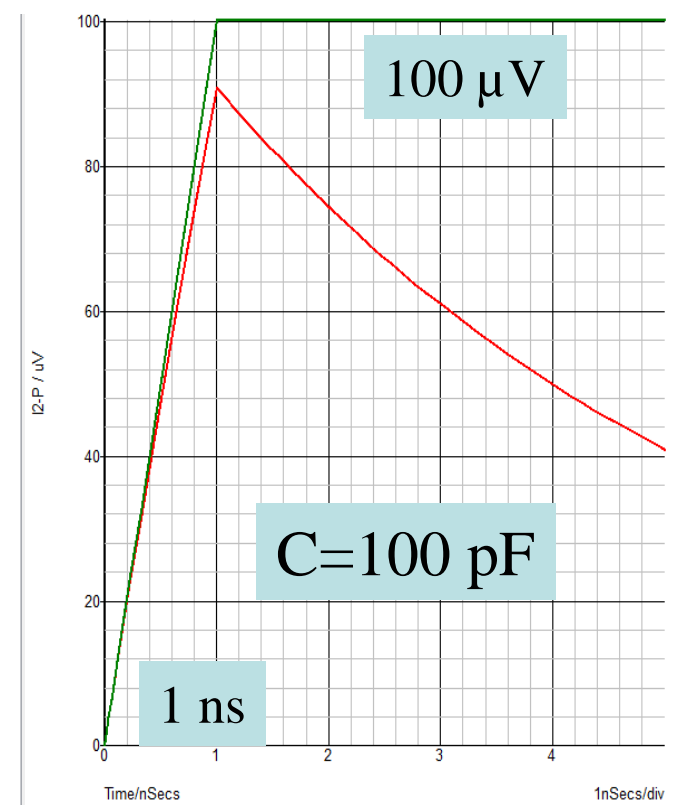
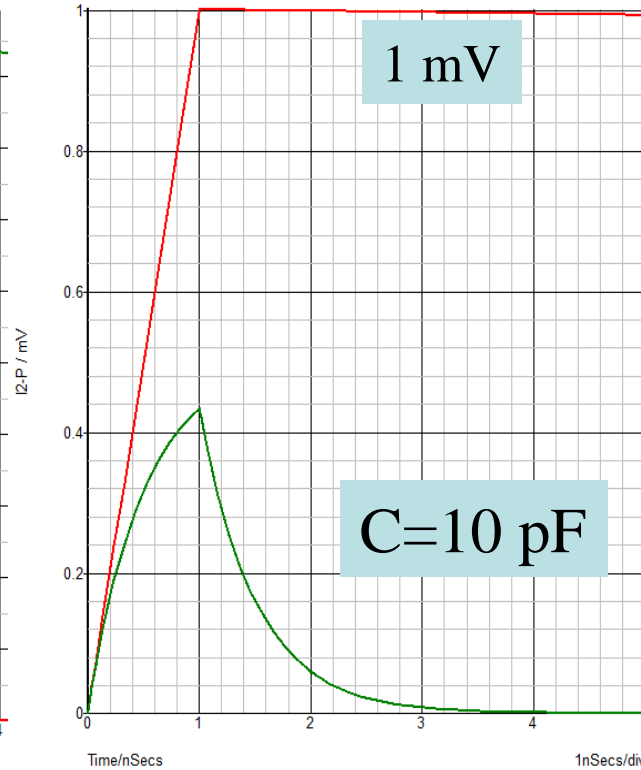
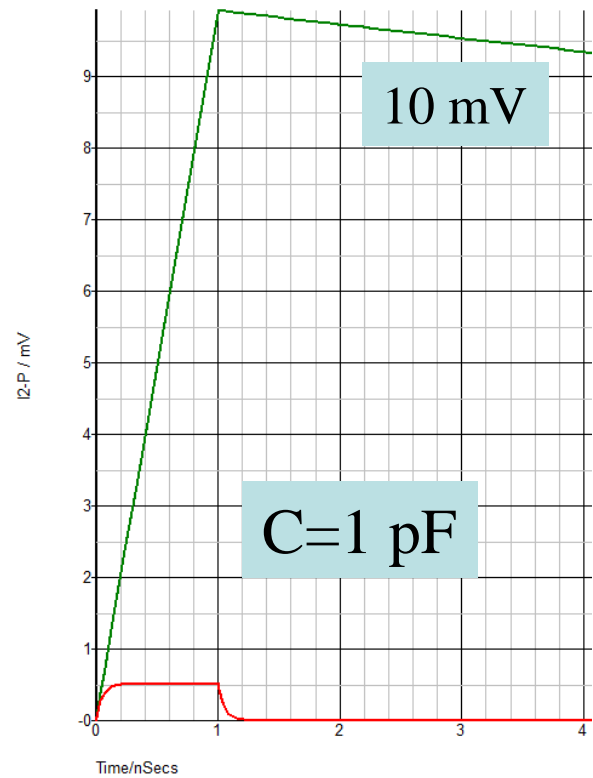
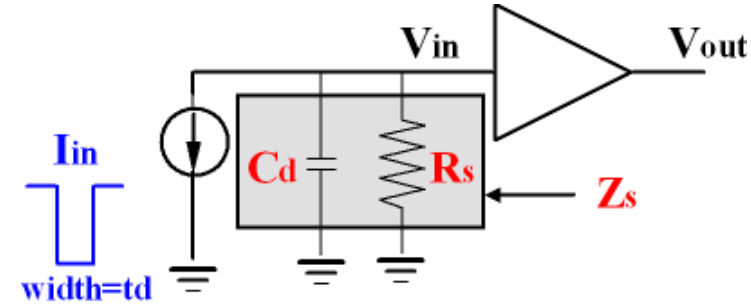
- Good shape as expected
- Adjustable conveyor gain
- Dynamic range as expected: TOT (12bit) – 300pC aimed
- Single-Photon Spectra (SPS):
 - 4V overvoltage, conveyor gain = 12
 - Gain: ~ 10 ADC counts



- Lots of interest for ~ 10 ps timing resolution
- Most of our work (so far) focused on Si, LGADs and SiPMs
- Studies of PETIROC and LIROC with MGRPCs by Imad et al.

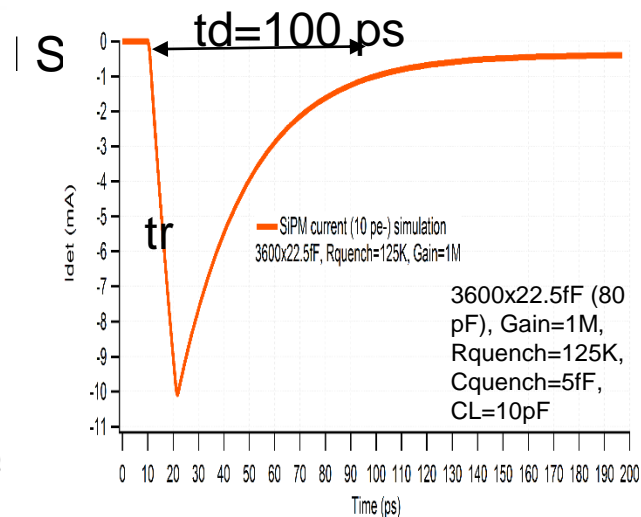
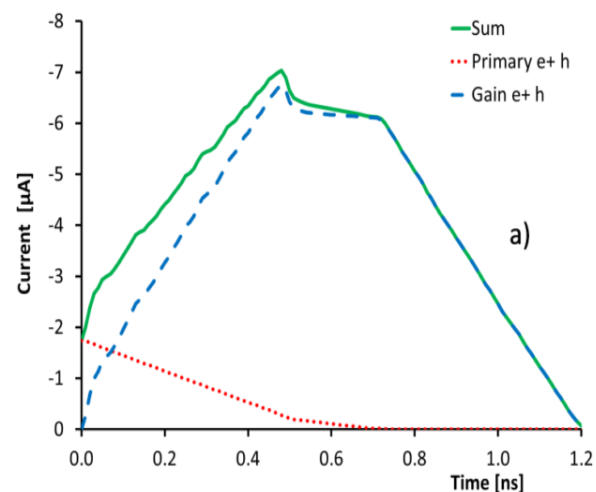
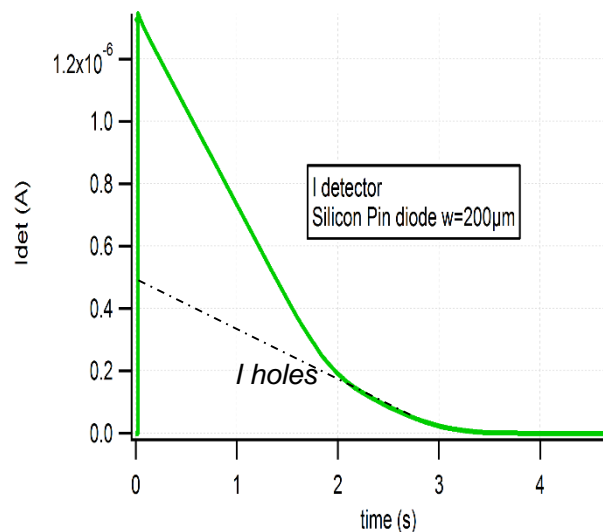
		sensor	polarity	BW	Zin	Cd	TDC	dyn range	FOM	min thresh	"@Cd="
PETIROC	VPA	SiPM/RPC	both	900 MHz	200	10-100 pF	25 ps			1 mV	
LIROC	VPA	SiPM/RPC	both	300 MHz	1k	10-100 pF	no	10fC-100 pC	2 ns/Q (fC)	40 fC	
ALTIROC	VPA/TZ	LGAD	neg	300-800 MHz	2k/200	1-10 pF	20 ps	0.1-50 fC	100 ps/Q(fC)	2 fC	5 pF
HGCROC	TZ	Si	neg	100 MHz	40	10-100 pF	25 ps	0.1 fC-10 pC	2 ns/Q (fC)	20 fC	50 pF
H2GCROC	CC	SiPM	pos	80 MHz	25	100p-1nF	25 ps	10 fC-200 pC			

- Example : $10 \text{ fC} - 1 \text{ ns} \Rightarrow i = 10 \text{ uA}$
- signal from 1-10-100 pF sensors into 50Ω (current) or 50k (voltage) preamp



Signal : detector current

- PN diode $w = 200\mu\text{m}$
- Very short rise time : $t_r \sim 10\text{ps}$
- Relatively long «drift time» : $t_d \sim 2\text{ns}$
- LGAD sensor $w = 50\mu\text{m}$
- rise time : $t_r \sim 500\text{ps}$
- Decay time» : $t_d \sim 700\text{ps}$
- SiPM detector (10pe-)
- very short rise time : $t_r \sim 10\text{ps}$
- Short duration : $t_d \sim 100\text{ps}$,

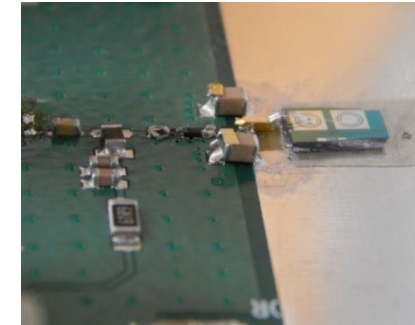


© Harmut Sadrozinski (Santa Cruz) “the beautiful risetime of the detector is spoilt by the electronics”

- NA62 tracker : PIN diode thickness 300 μm $A=0.09 \text{ mm}^2$
 - $C_d = 0.1 \text{ pF}$ $e_n = 11 \text{ nV}/\sqrt{\text{Hz}}$ $t_d = 3 \text{ ns}$ $\sigma = 60 \text{ ps}/\text{Q}(\text{fC})$
 - 1 MIP = 3 fC $\Rightarrow \sigma = 20 \text{ ps}/\#\text{MIP}$ ($\sim 60\text{-}200 \text{ ps}$ measured)

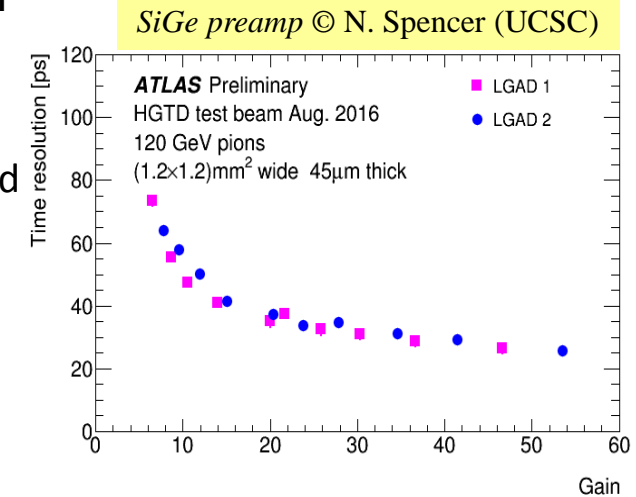
$$\sigma_t^J = \frac{e_n C_d}{Q_{in}} \sqrt{t_d}$$

- CMS HGCal : PIN diode thickness 300 μm $A=25 \text{ mm}^2$
 - $C_d = 8 \text{ pF}$ $e_n = 1 \text{ nV}/\sqrt{\text{Hz}}$ $t_d = 3 \text{ ns}$ $\sigma = 420 \text{ ps}/\text{Q}(\text{fC})$
 - 1 MIP = 3.8 fC $\Rightarrow \sigma = 110 \text{ ps}/\#\text{MIP}$ ($\sim 200 \text{ ps}$ measured)

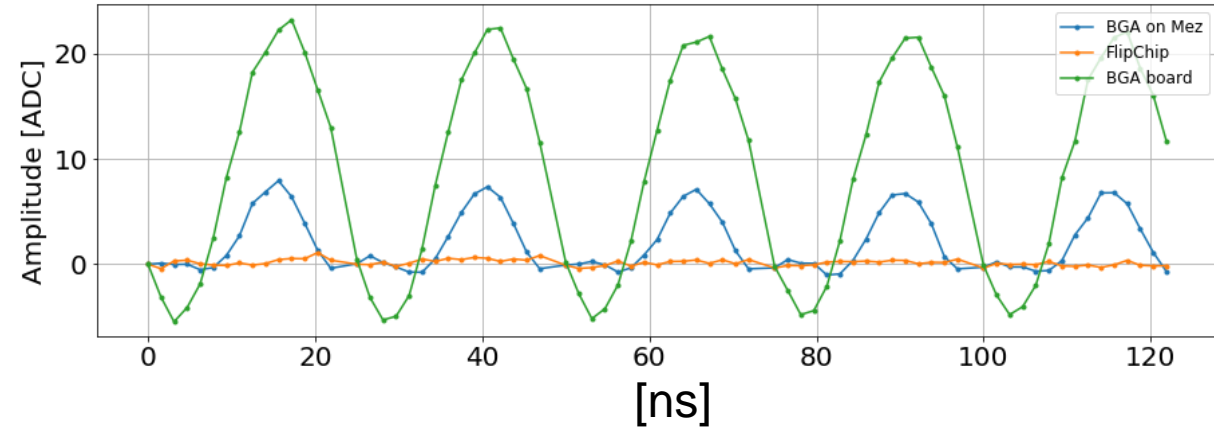


- ATLAS HGTD : LGAD diode thickness 50 μm $A= 2 \text{ mm}^2$
 $G = 10$
 - $C_d = 2 \text{ pF}$ $e_n = 2 \text{ nV}/\sqrt{\text{Hz}}$ $t_d = 0.5 \text{ ns}$ $\sigma = 50 \text{ ps}/\text{Q}(\text{fC})$
 - 1 MIP = 5 fC ($G=10$) $\Rightarrow \sigma = 10 \text{ ps}/\#\text{MIP}$ ($\sim 40 \text{ ps}$ measured)

- SiPM $G = 10^6$
 - $C_d = 300 \text{ pF}$ $e_n = 1 \text{ nV}/\sqrt{\text{Hz}}$ $t_d = 100 \text{ ps}$ $\sigma = 3 \text{ ns}/\text{Q}(\text{fC})$
 - 1 pe = 160 fC $\Rightarrow \sigma = 20 \text{ ps}/\#\text{pe}$ ($\sim 60 \text{ ps}$ measured)



- A 40 MHz modulation is visible on the analog signals
 - Comes from digital current spikes on preamp ground node
 - 10 μV on ground give 1 ADC count
 - BGA worse than flip chip
 - BGA substrate optimised, improvements made by optimizing decoupling & the pcb ground impedance
 - Further improved by removing decoupling caps !
 - Reduces digital current spikes (inductance)



- This provides recommendations for the Hexaboard design
 - Very delicate design!

